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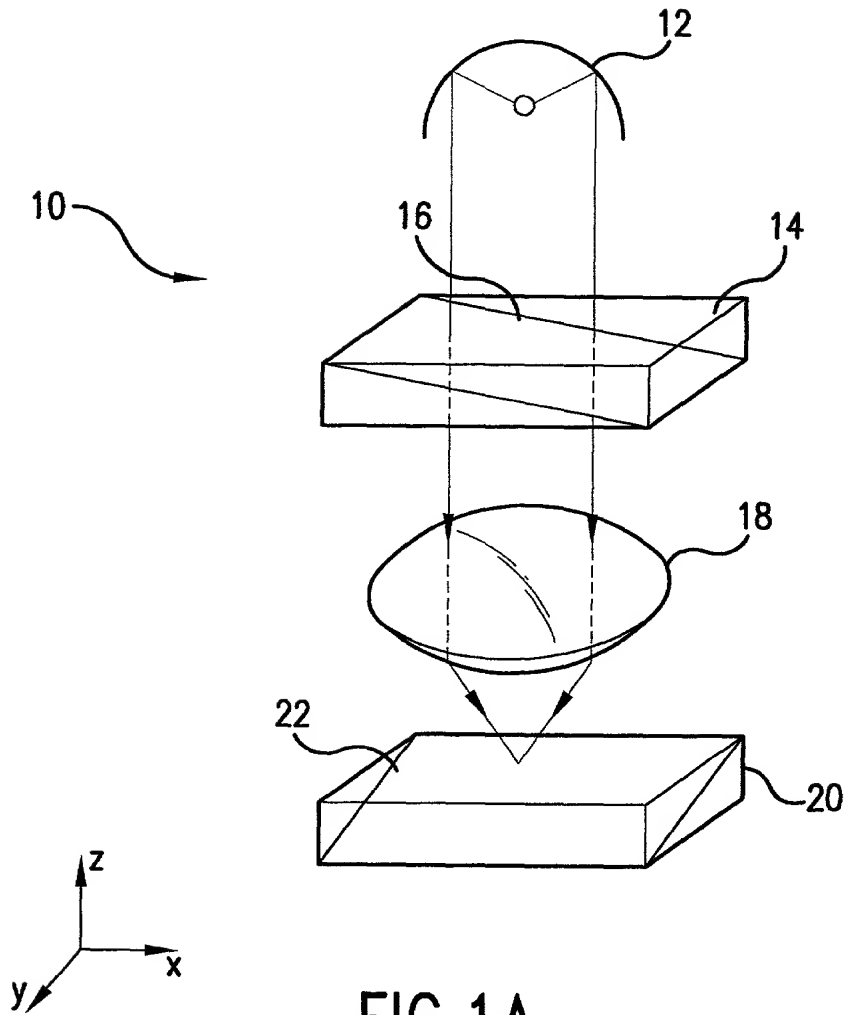


FIG.1A

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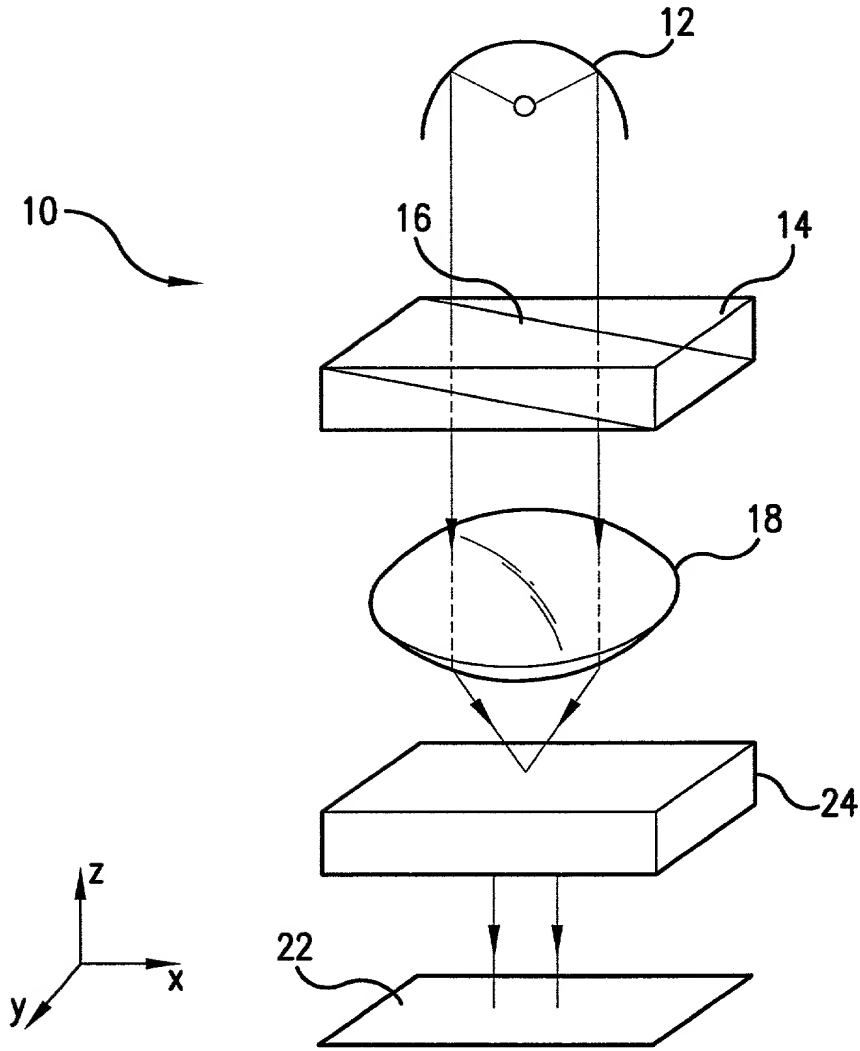


FIG. 1B

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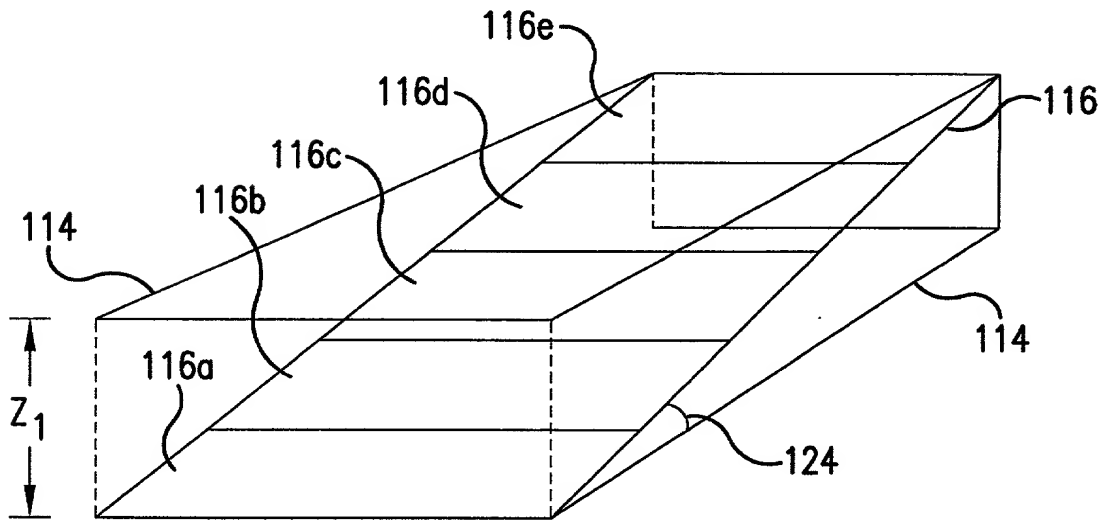


FIG. 2

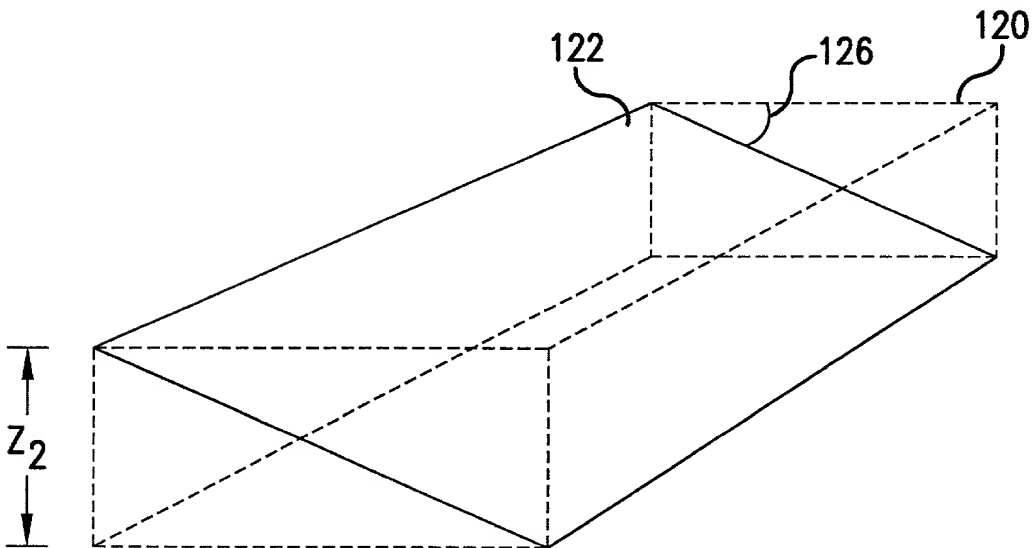


FIG. 3

FIG. 2 OF 206,0660

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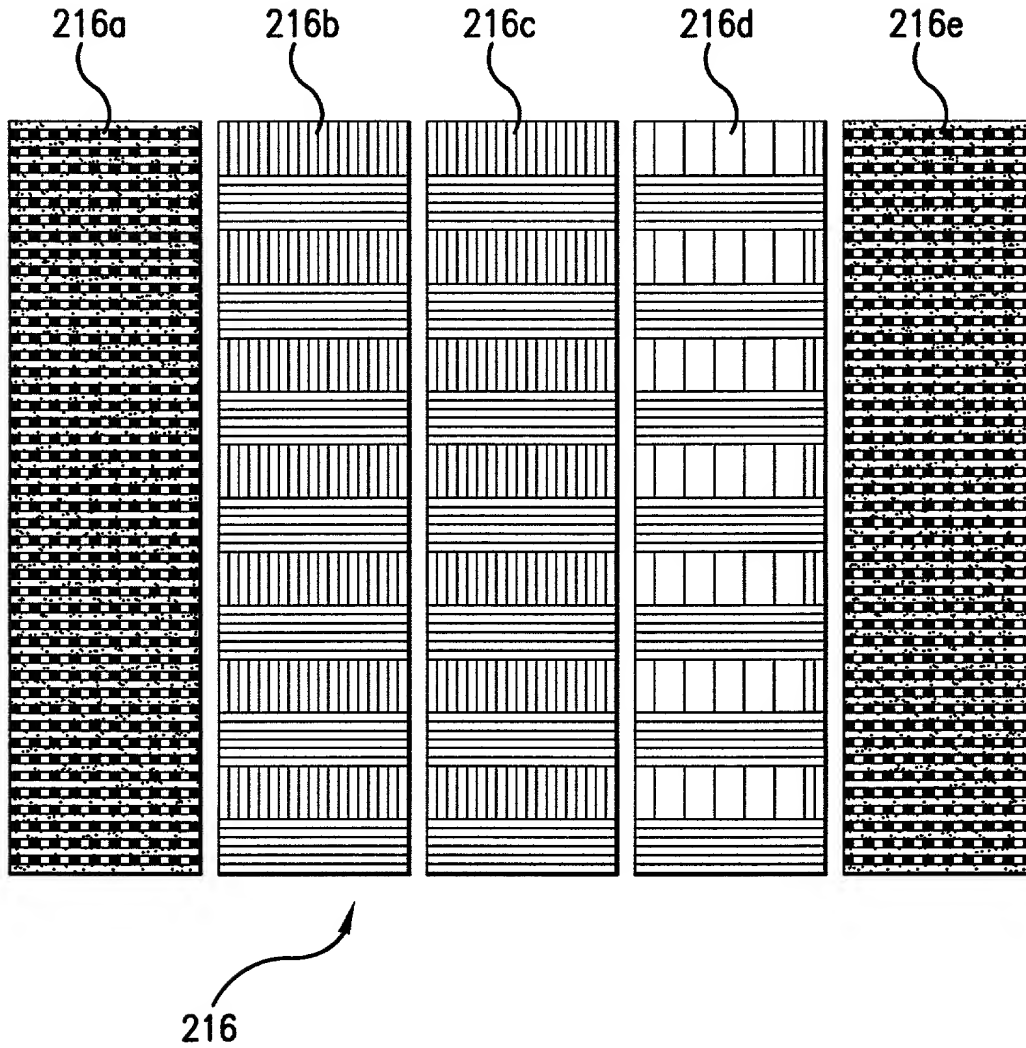


FIG. 4

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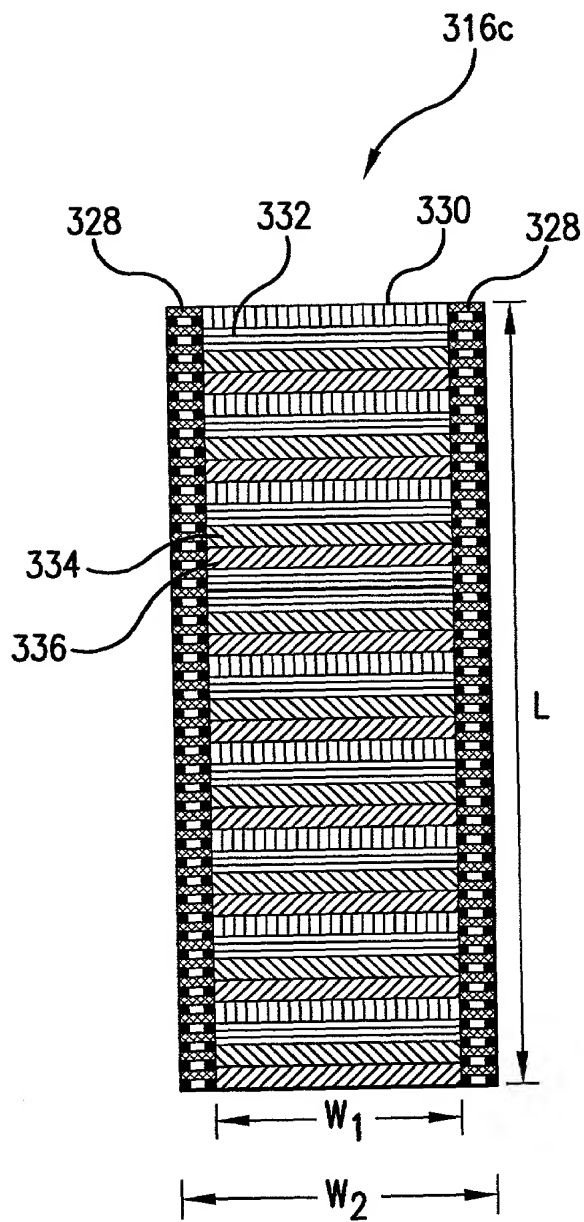


FIG. 5A

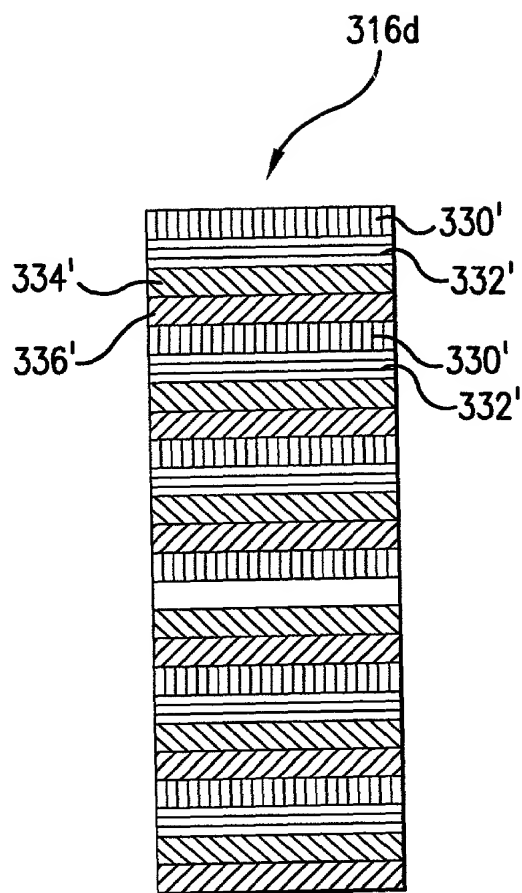


FIG. 5B

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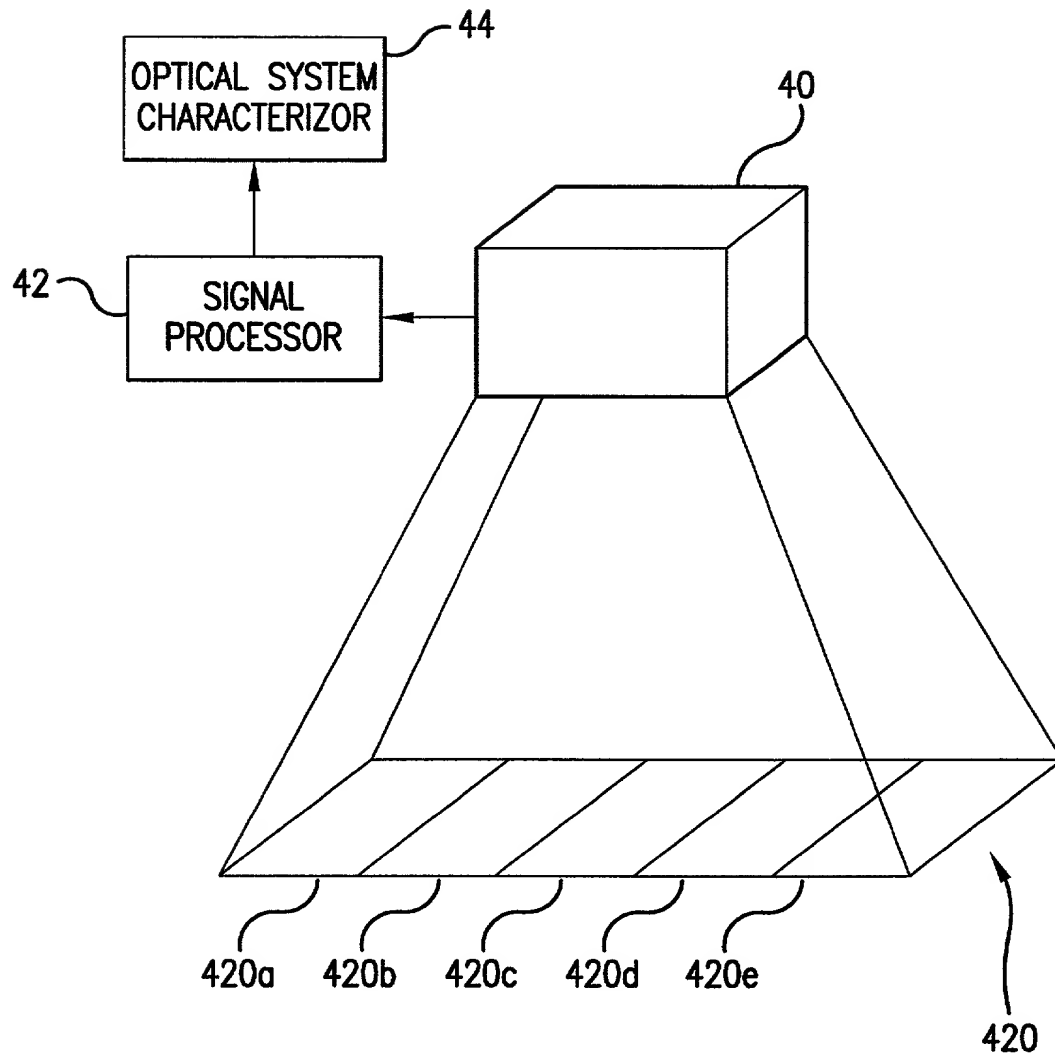


FIG.6

FIG. 6 of 39

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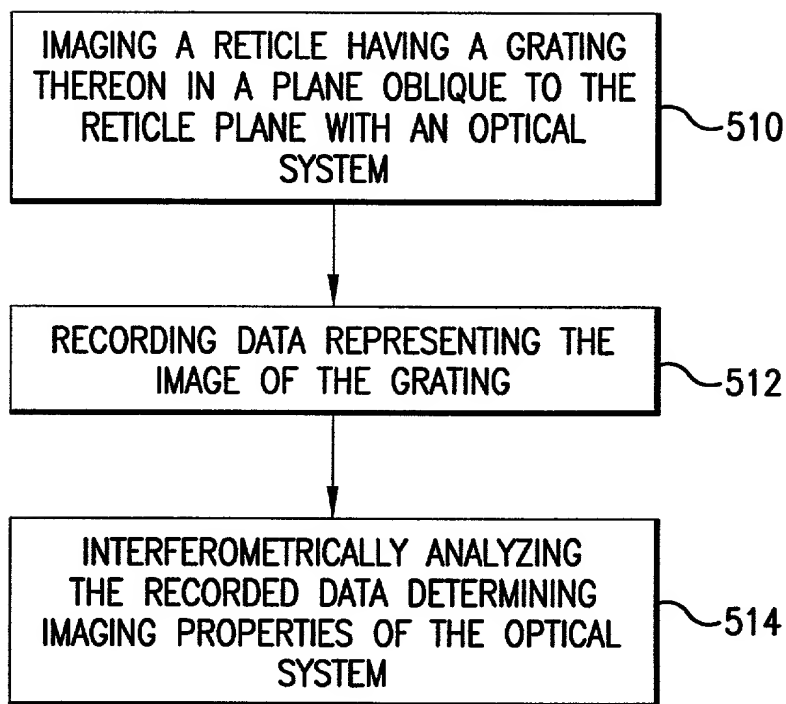


FIG.7

FIG. 7

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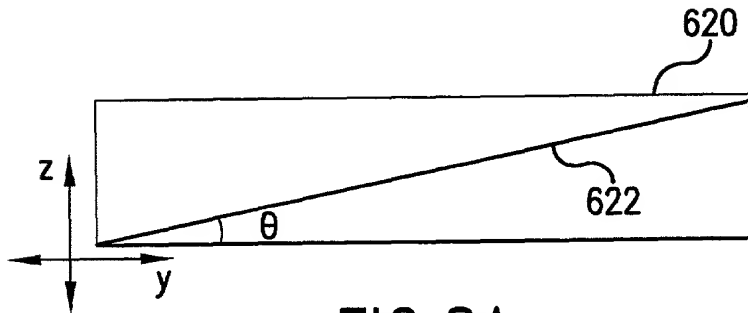


FIG. 8A

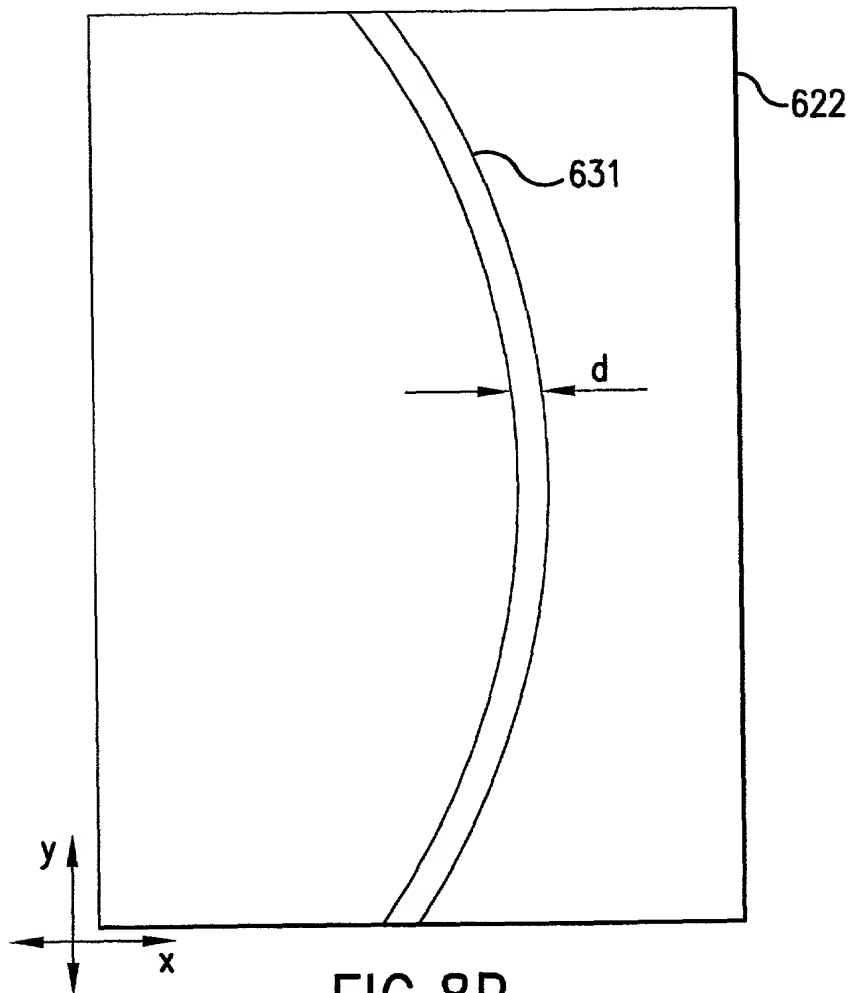


FIG. 8B

FIG. 8A

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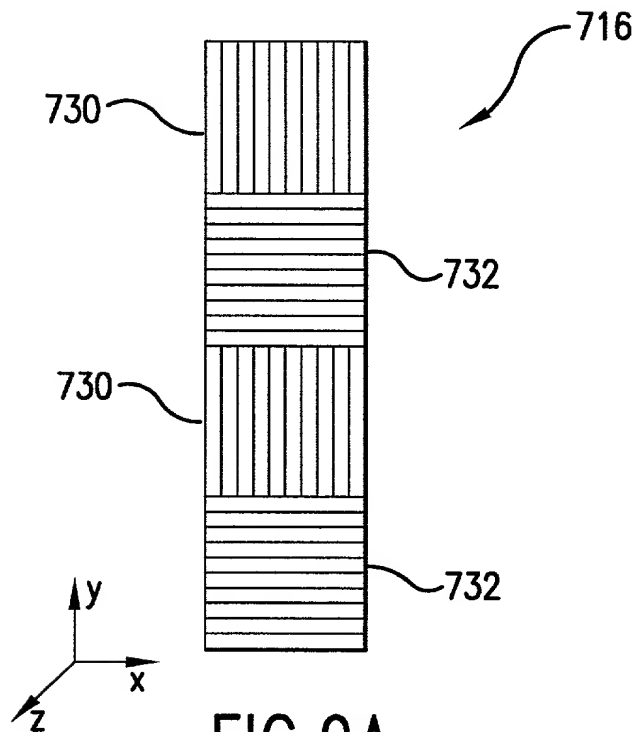


FIG. 9A

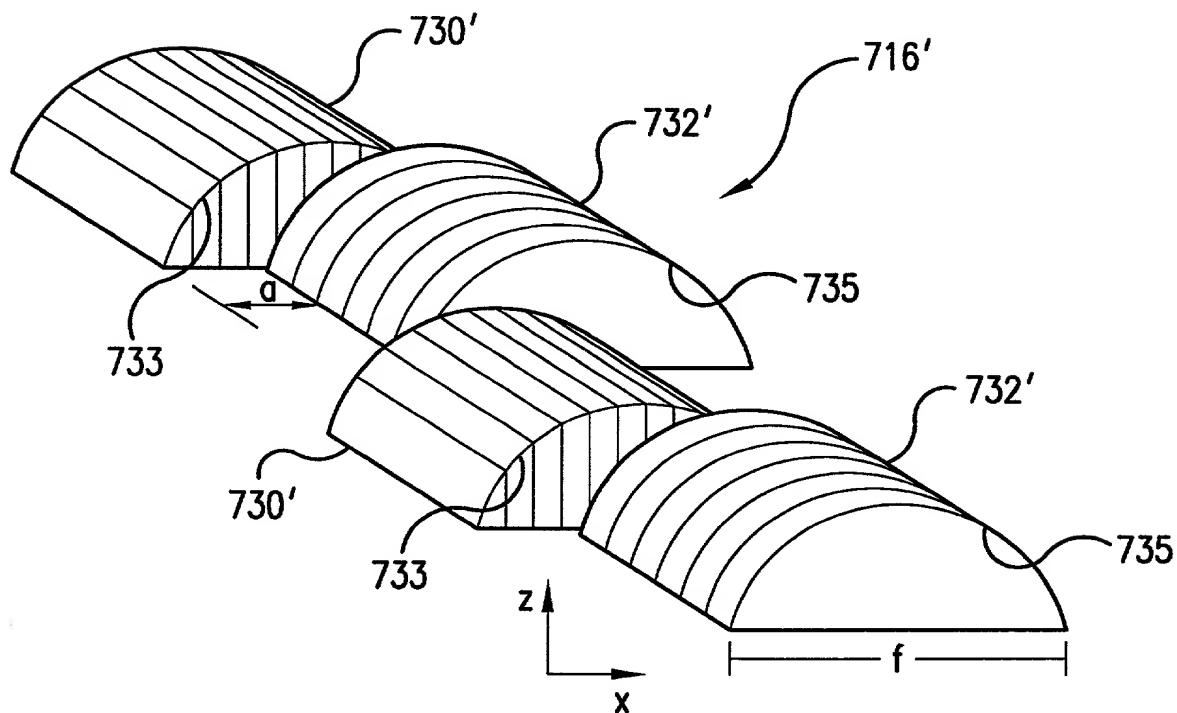


FIG. 9B

FIG. 9A

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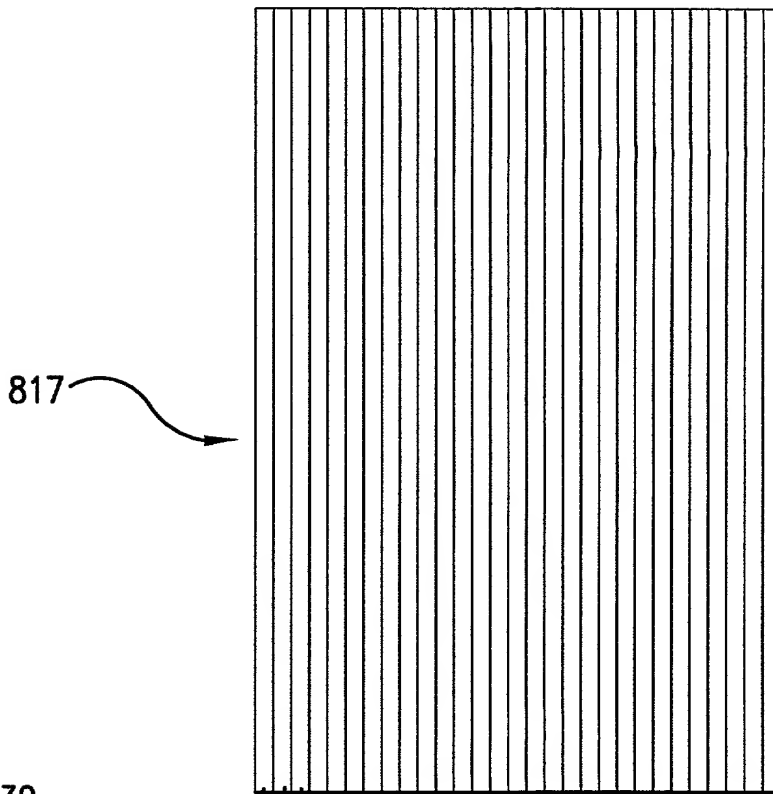


FIG.10A

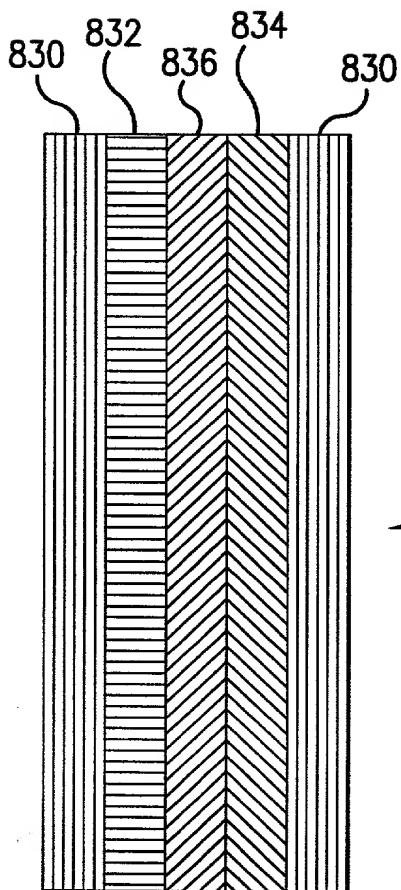


FIG.10B

FIG. 10A

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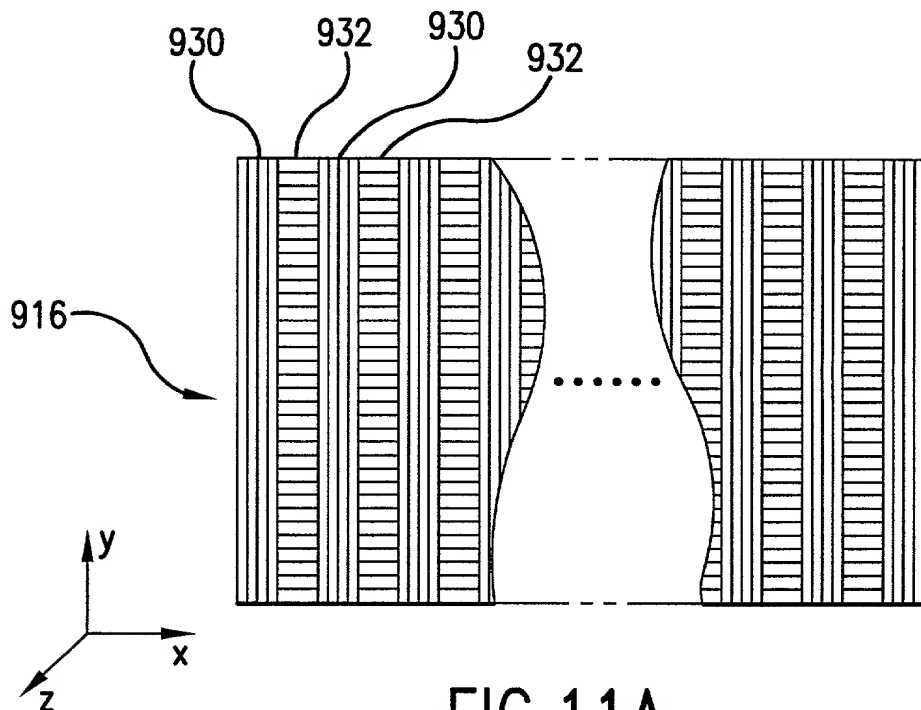


FIG. 11A

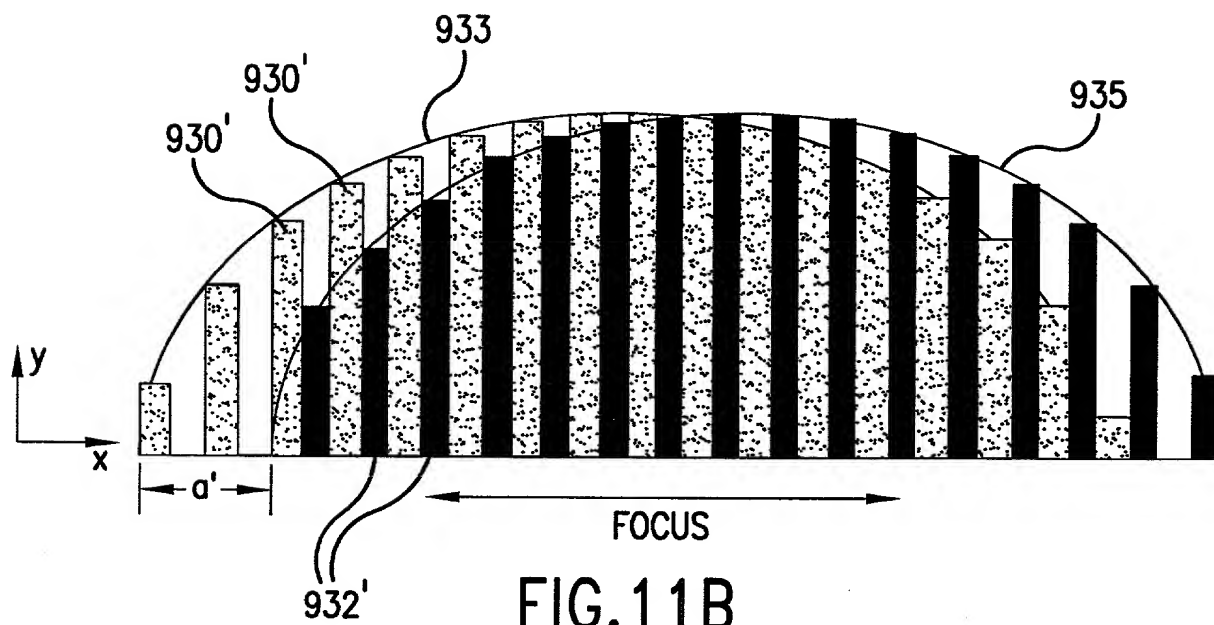


FIG. 11B

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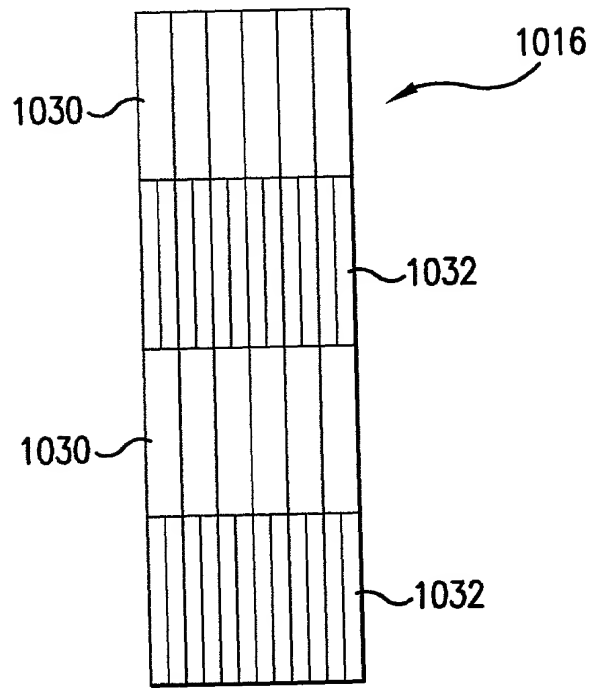


FIG. 12

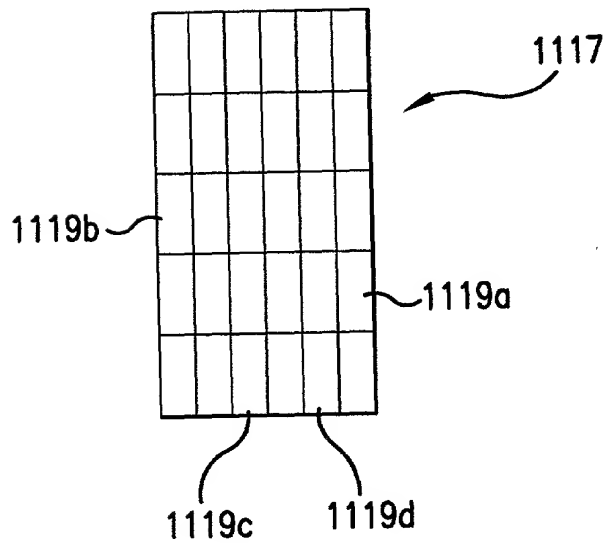


FIG. 13

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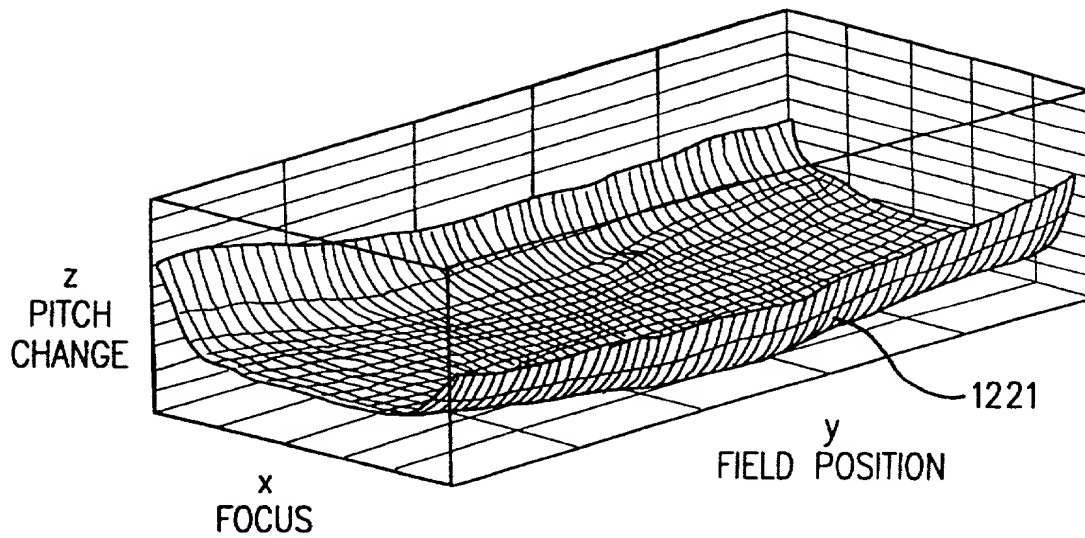


FIG. 14

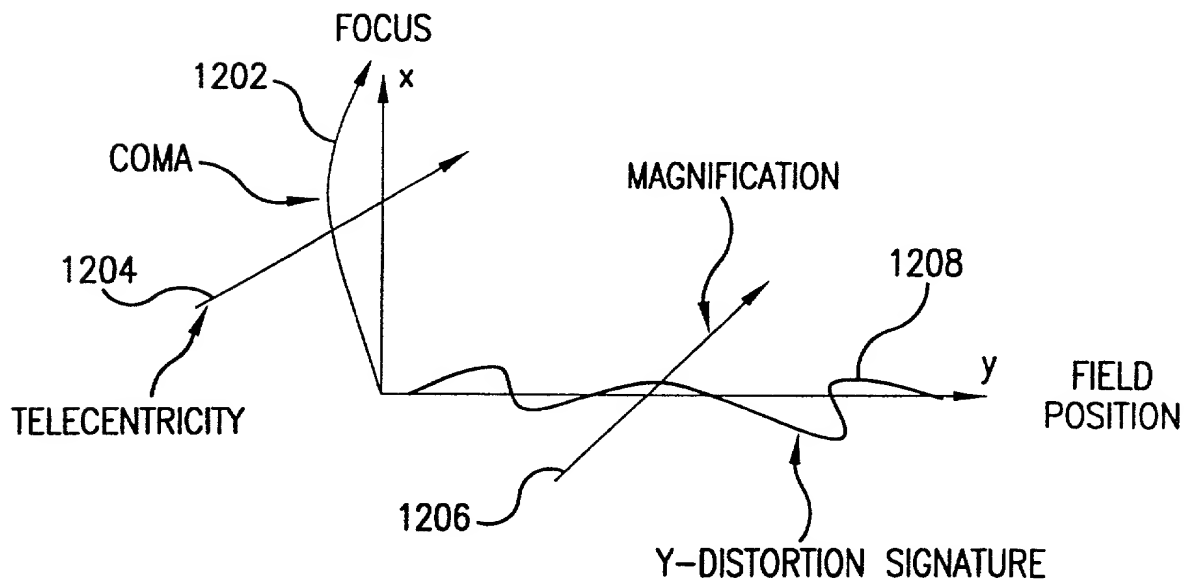
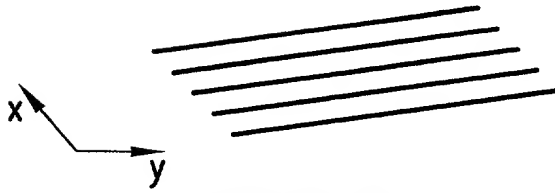


FIG. 15

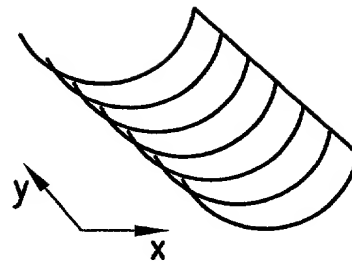
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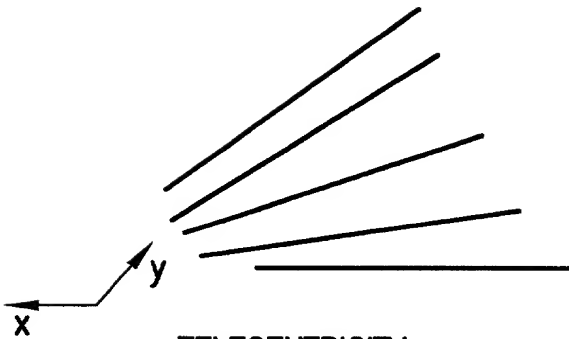
MAGNIFICATION

FIG.16A



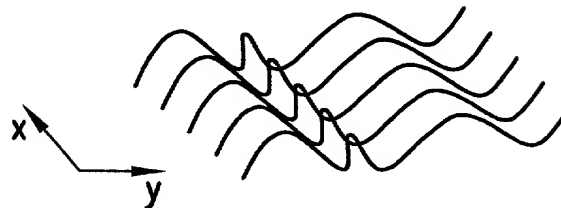
COMA

FIG.16B



TELECENTRICITY

FIG.16C



Y-DISTORTION SIGNATURE

FIG.16D

FIG. 16A, FIG. 16B, FIG. 16C, FIG. 16D

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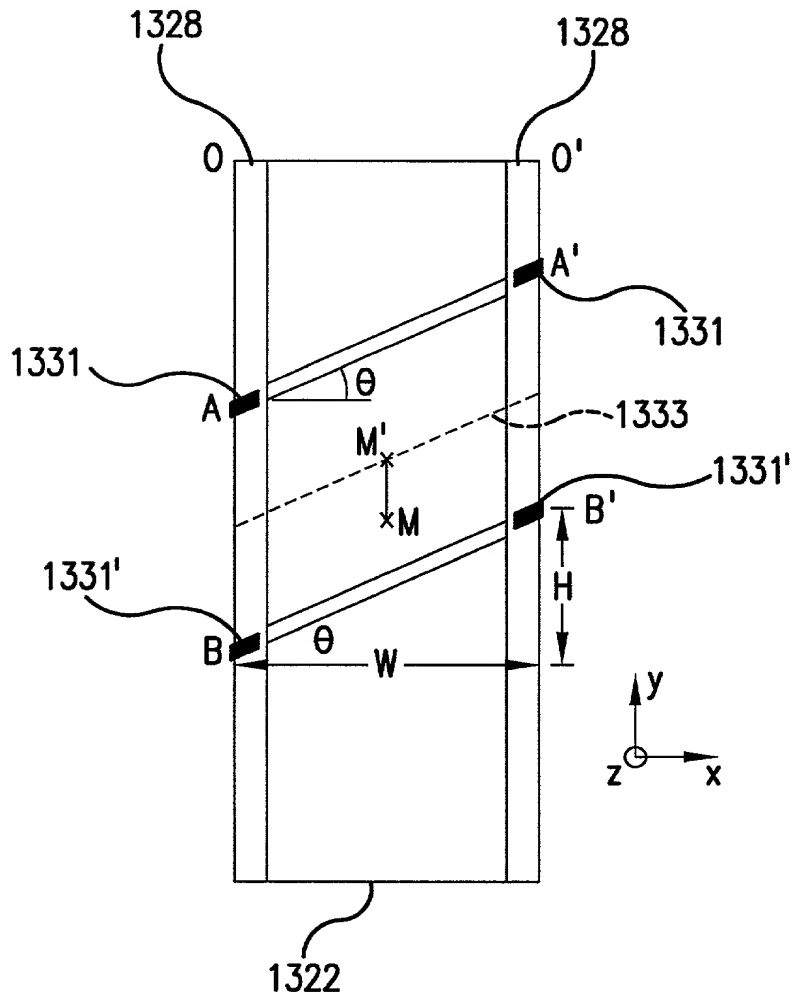


FIG.17

FIG. 17

Appl. No. 09/907,902; Group Art Unit: 2621
 Dkt. No. 1875.0300001;
 Inventor(s): Matthew E. Hansen; Tel: 202/371-2600
 Title: System and Method for Characterizing Optical System
 Using Holographic Reticles

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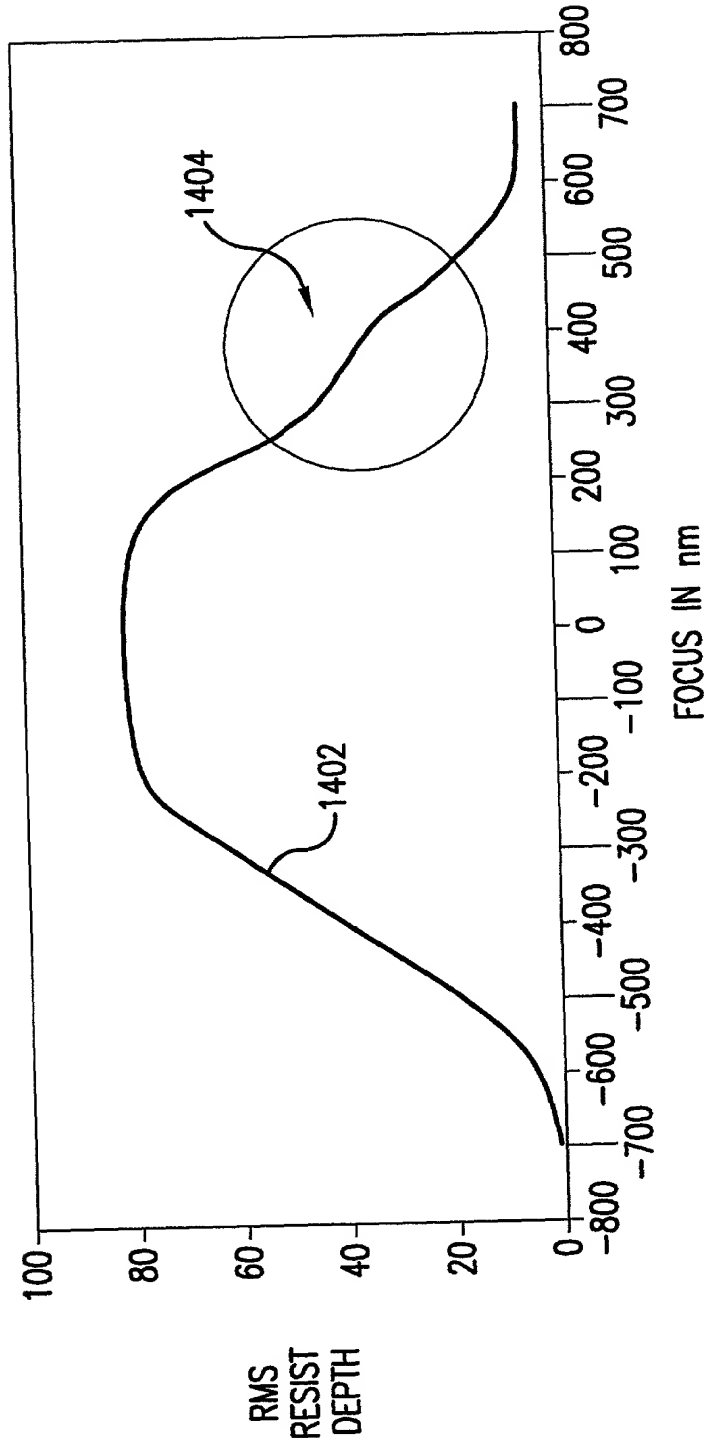


FIG.18

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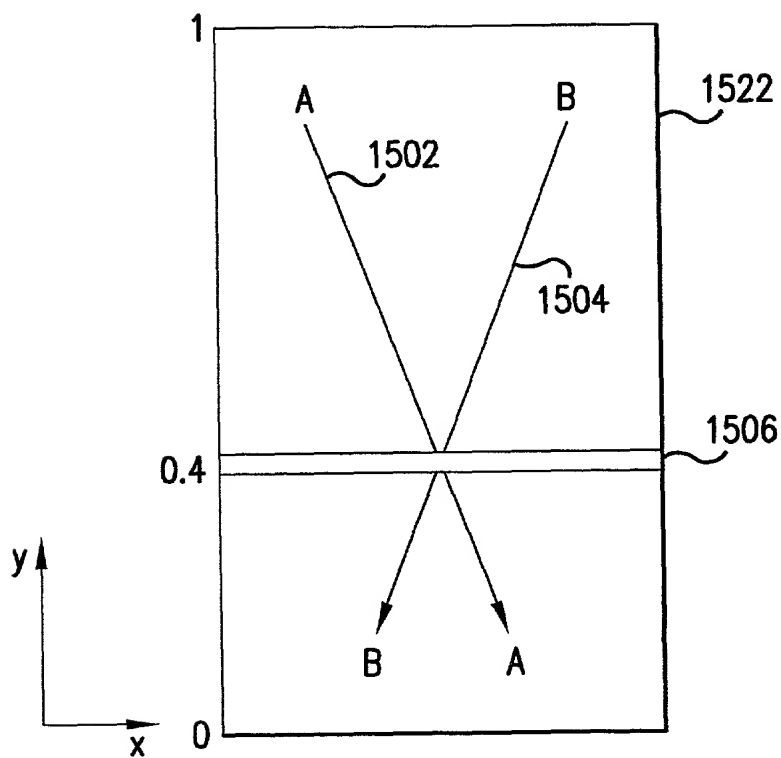


FIG.19A

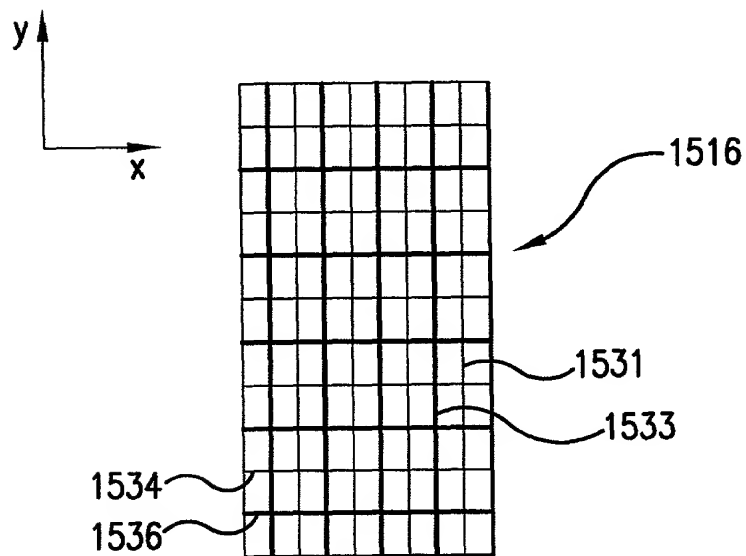


FIG.19B

FIG. 19A

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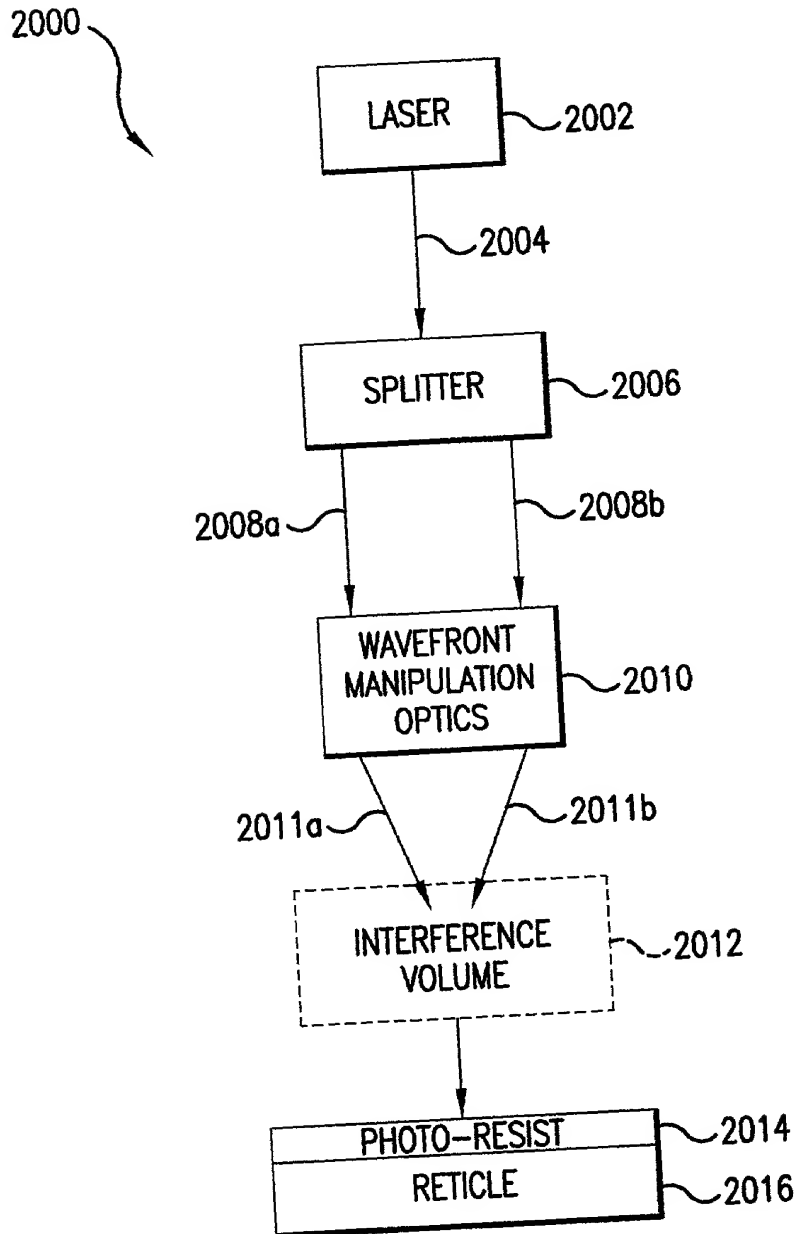


FIG.20

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2100

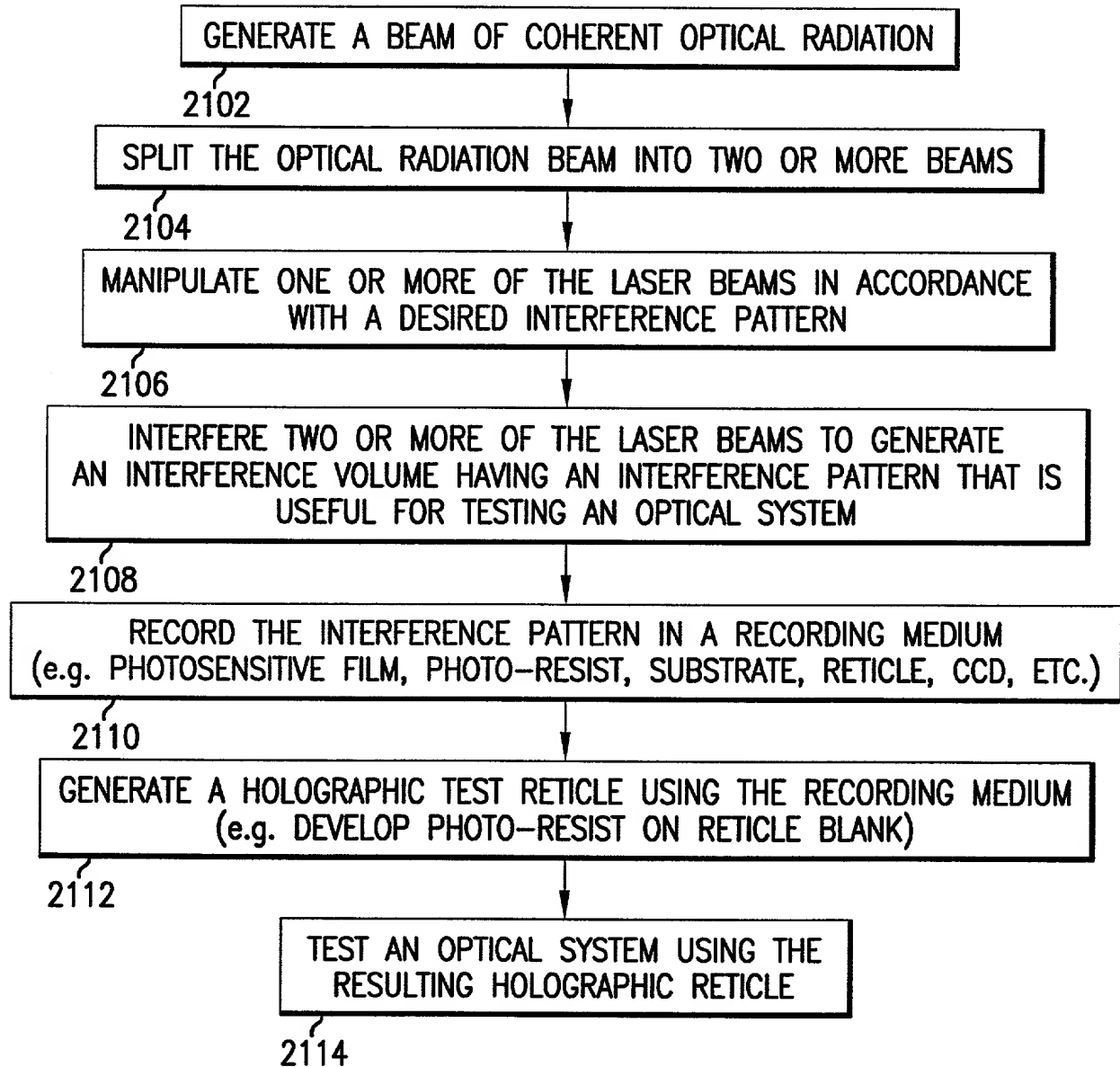


FIG.21

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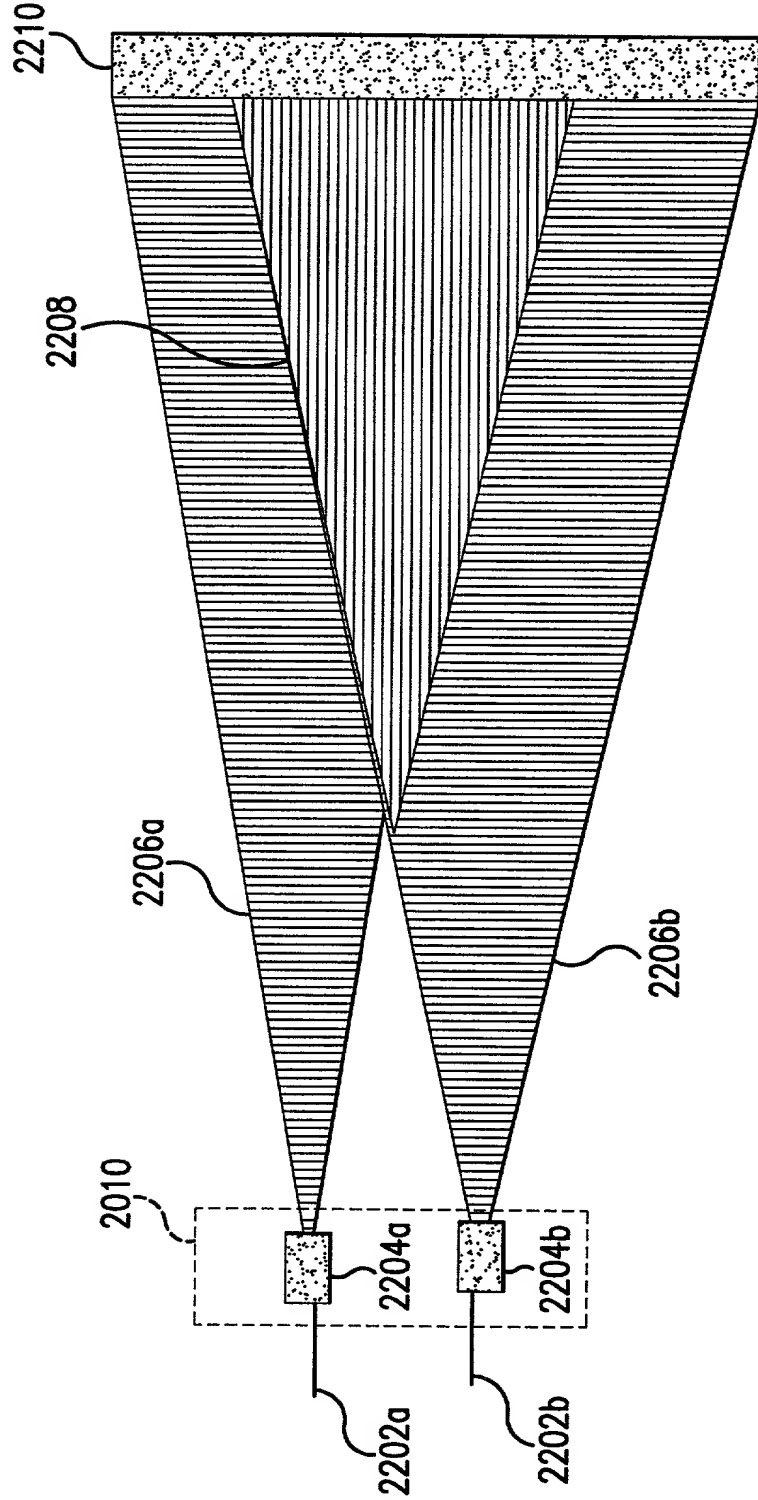


FIG. 22A

FIG. 22A

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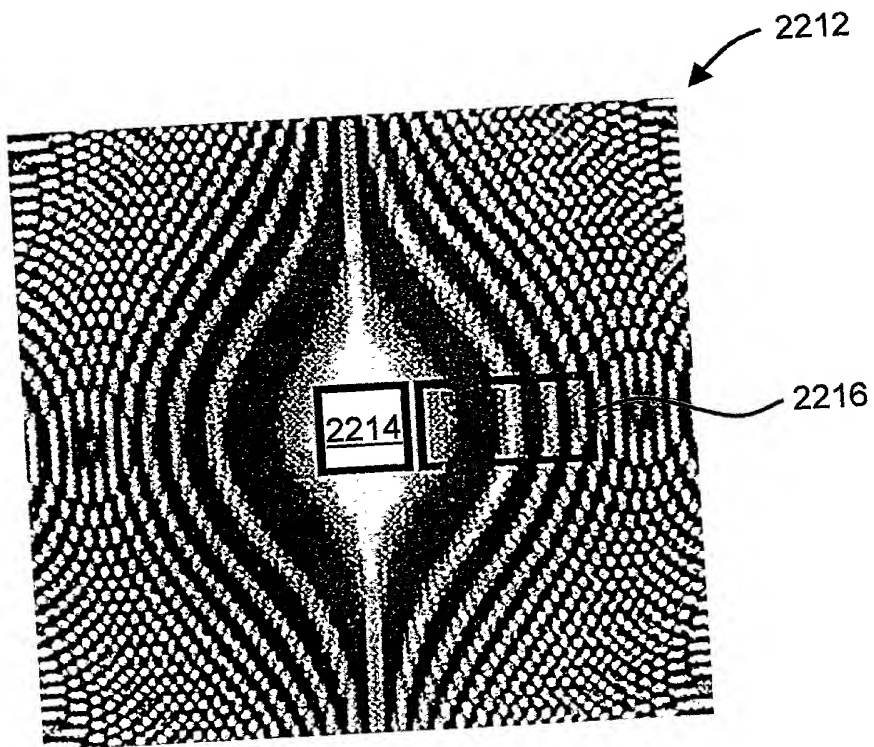
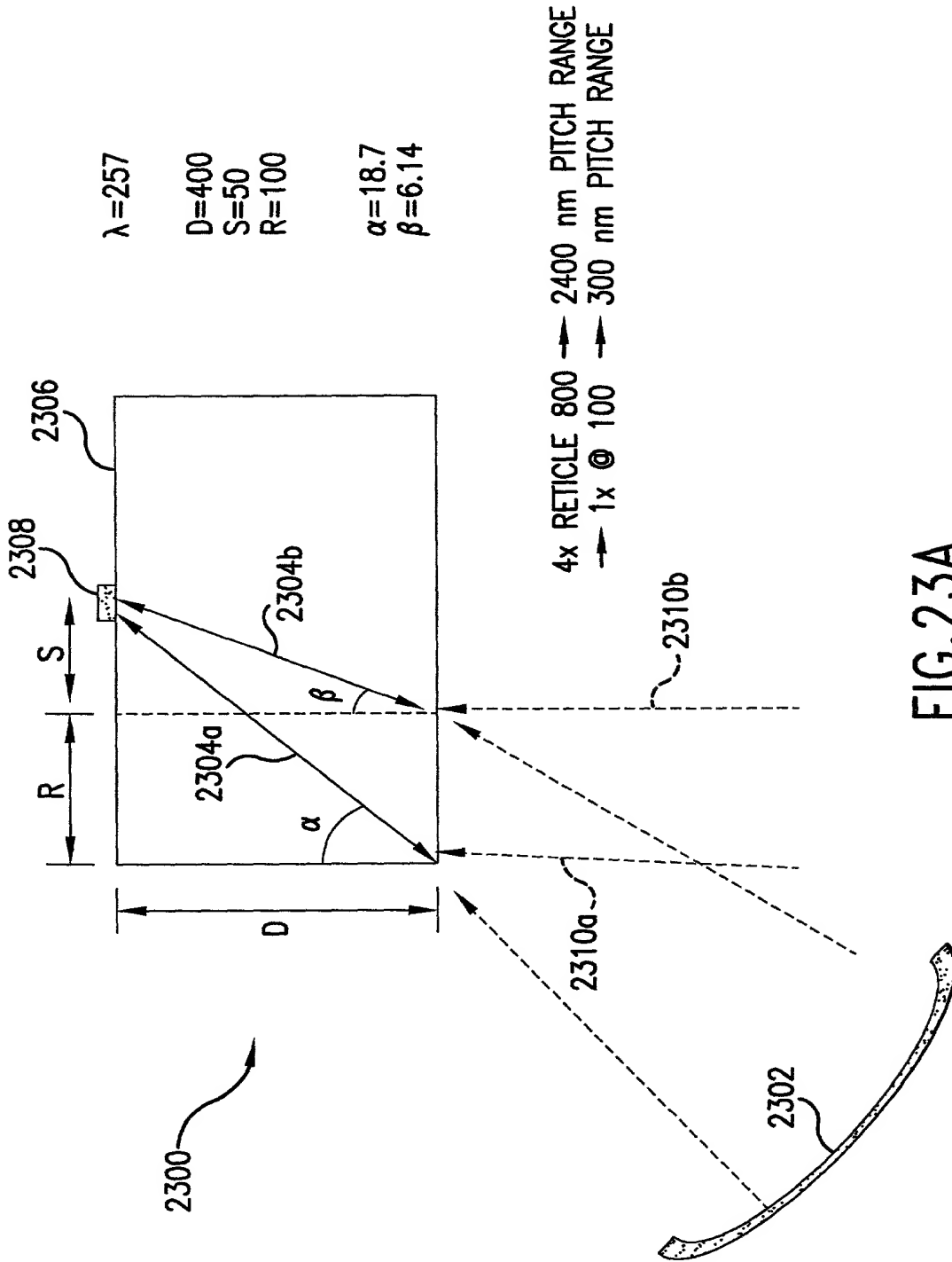


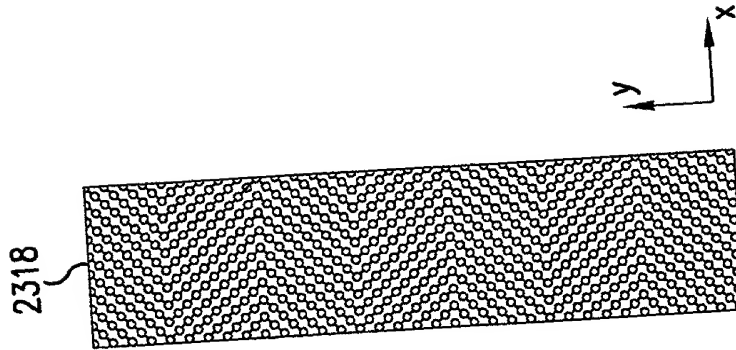
FIG. 22B

09907902-102901

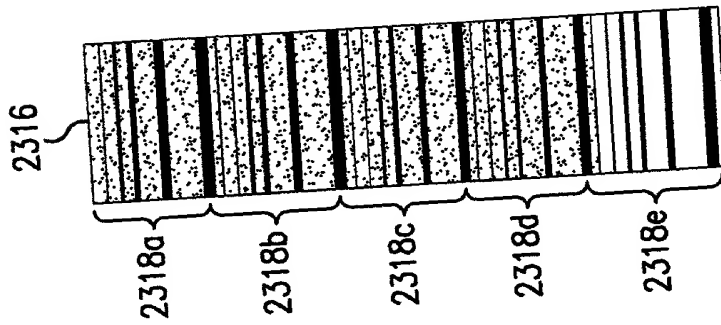
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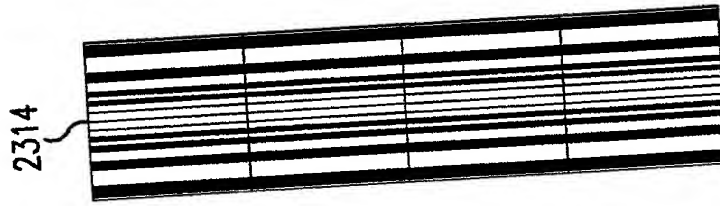
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CIRCULAR ZONE
 PLATE ARRAY
 FIG. 23E



INTERLACED CHIRPED
 HOLOGRAPHIC STRUCTURES
 FIG. 23D



REVERSE CYLINDER
 ZONE PLATE
 FIG. 23C



CYLINDER ZONE
 PLATE
 FIG. 23B

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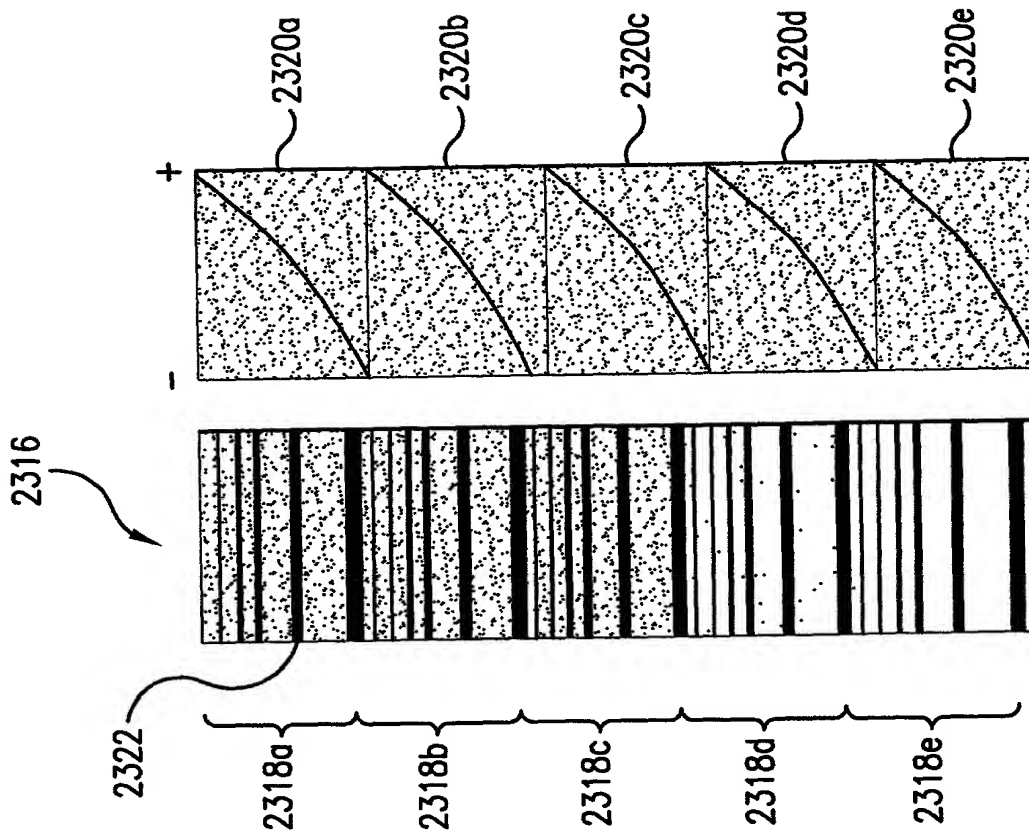


FIG. 23F

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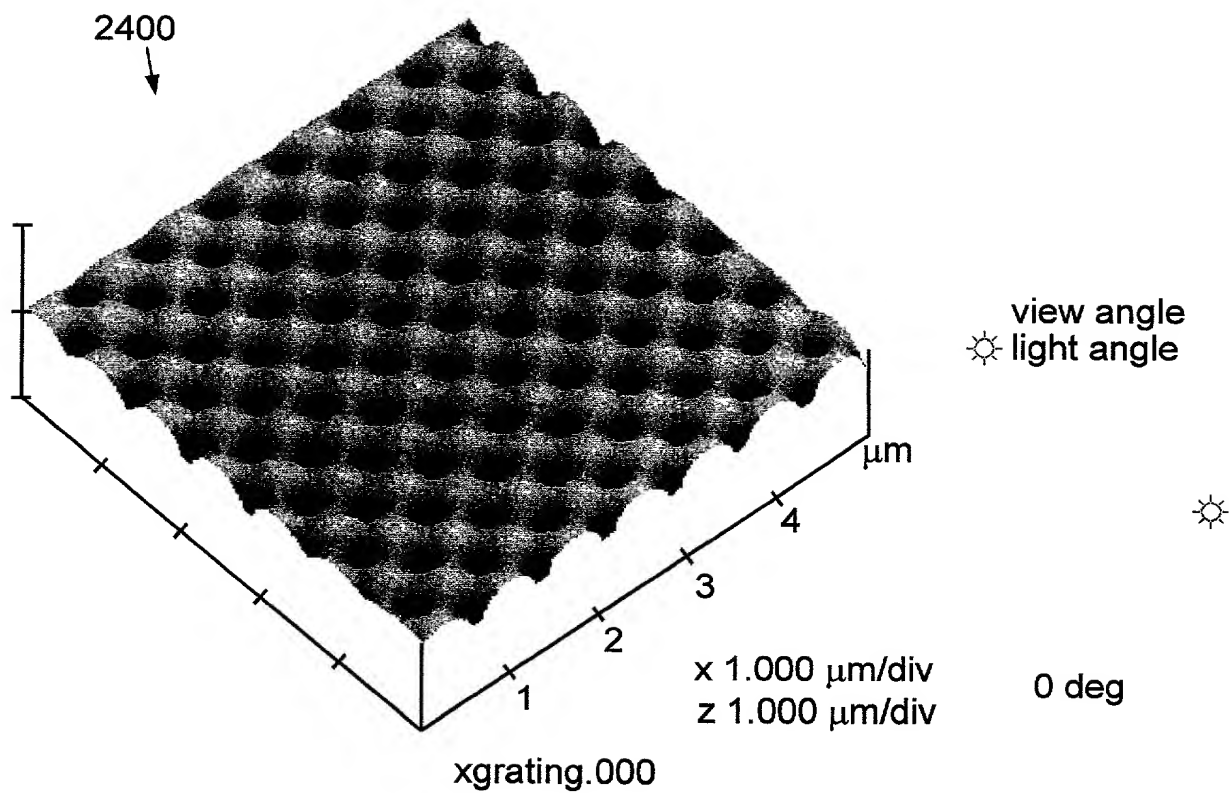


FIG.24

Appl. No. 09/907,902, Group Art Unit: 2621
Dkt. No. 1875.0300001;
Inventor(s): Matthew E. Hansen; Tel: 202/371-2600
Title: System and Method for Characterizing Optical System
Using Holographic Reticles

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2500

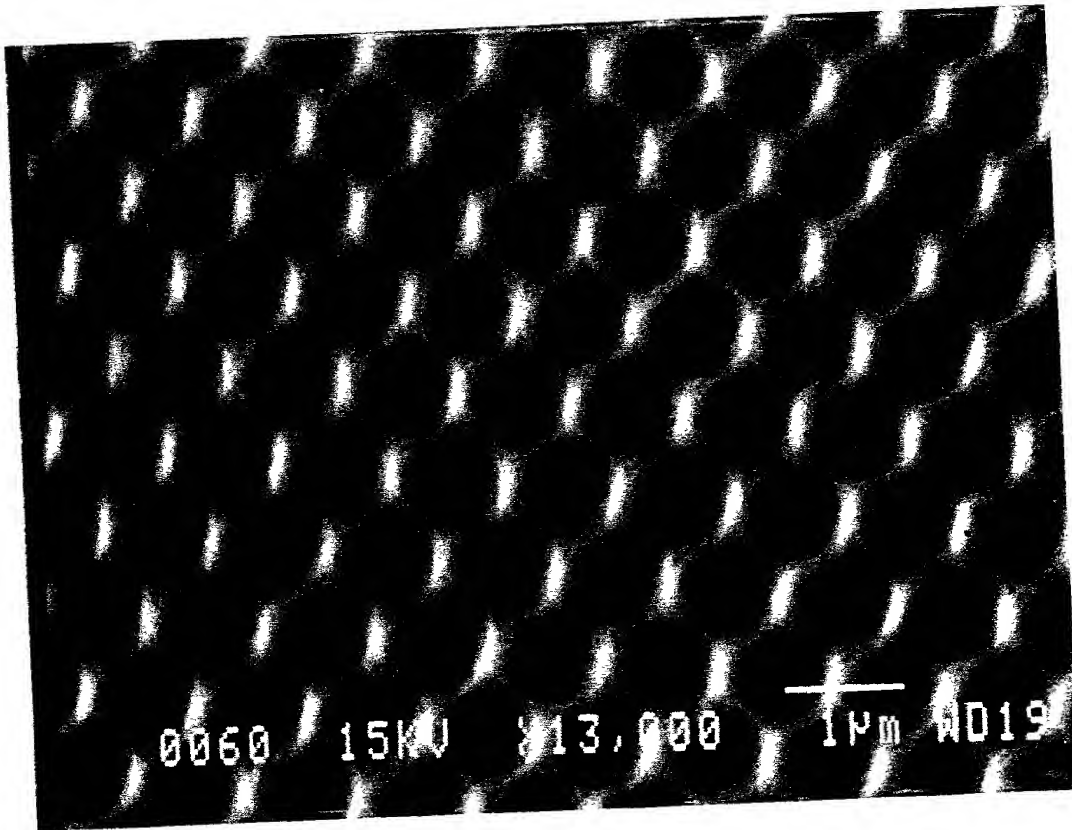


FIG.25

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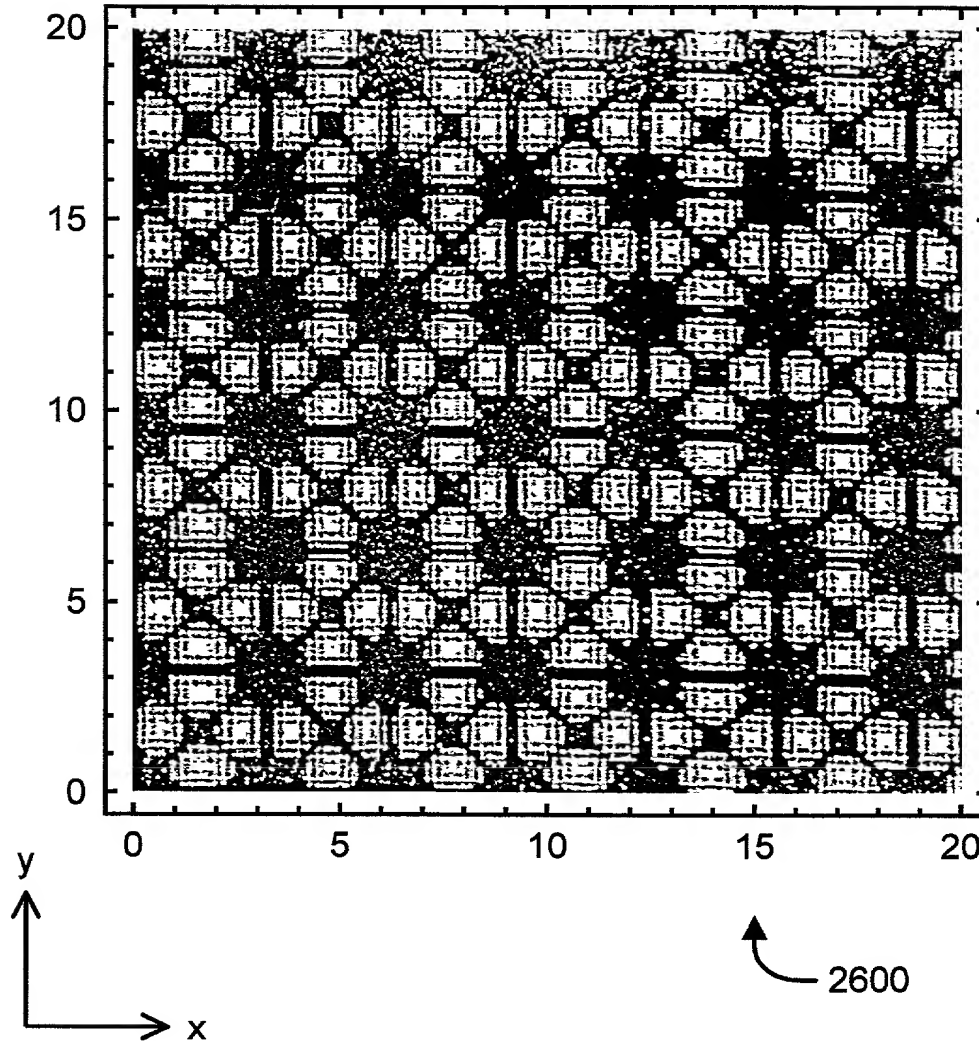


FIG.26

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2700

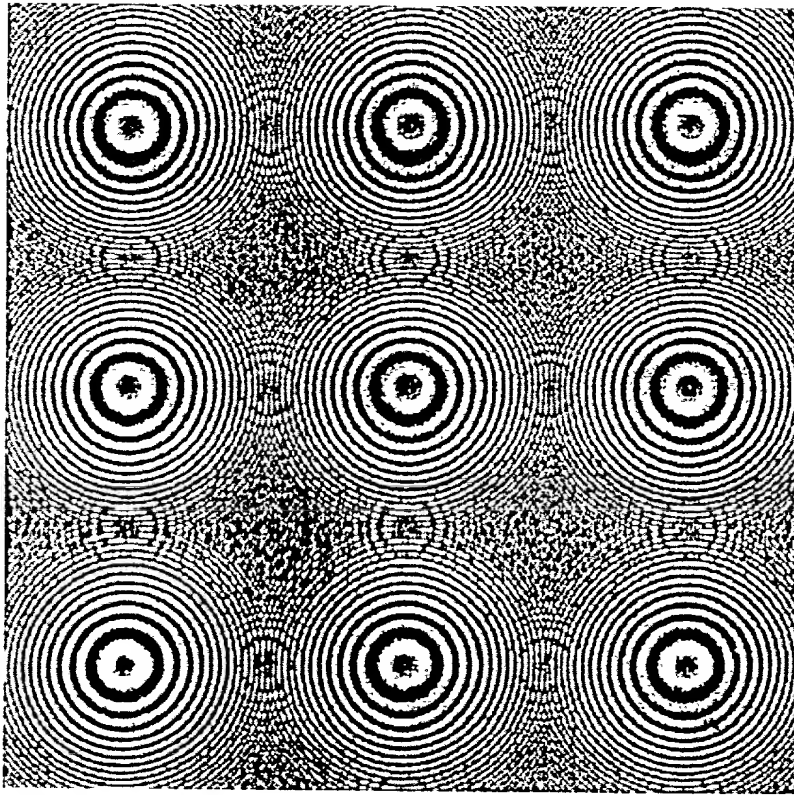


FIG.27

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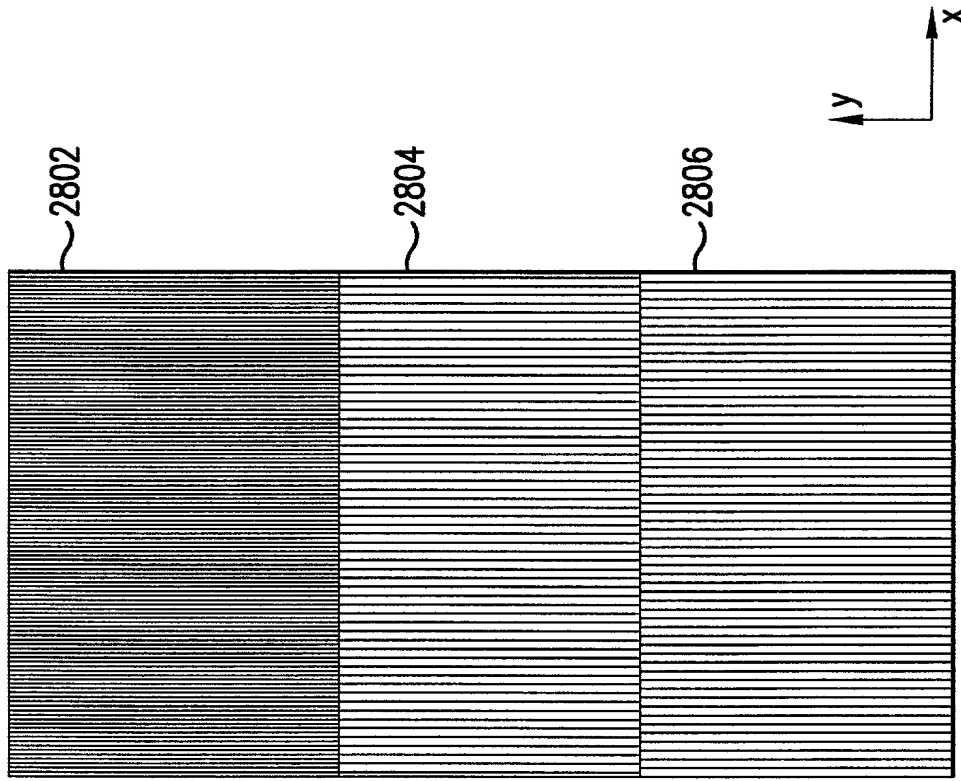


FIG.28

PITCH CHANGE

PHASE CHANGE

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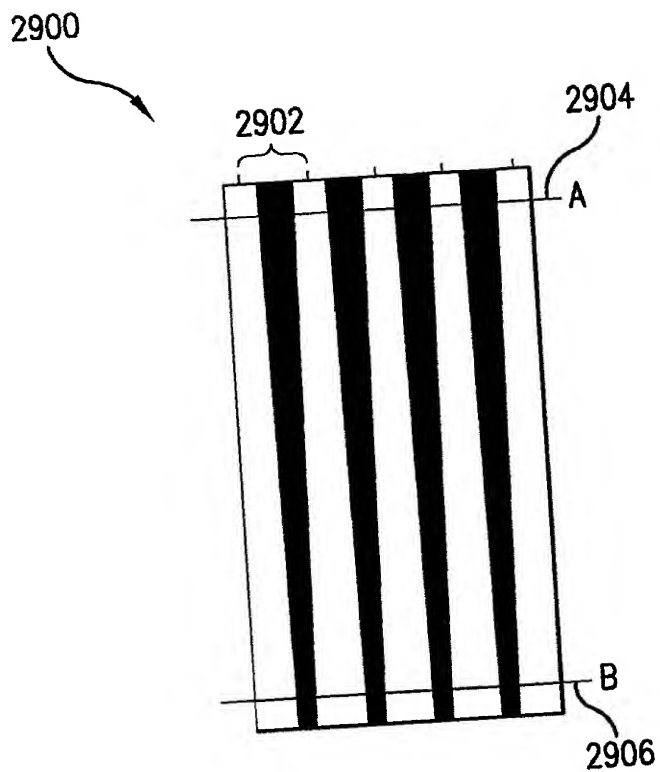


FIG.29A

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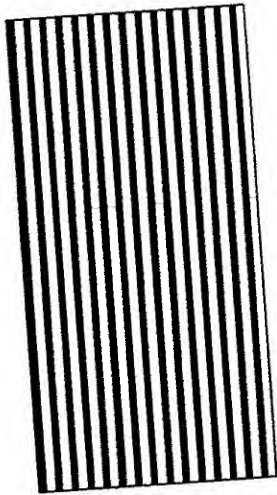
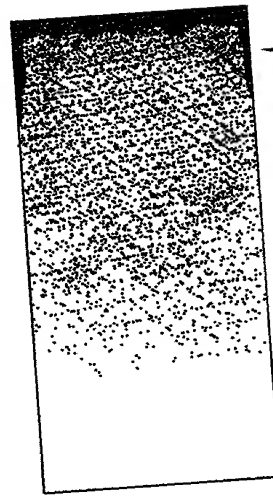


FIG. 29B

2910



2914

2912

FIG. 29C

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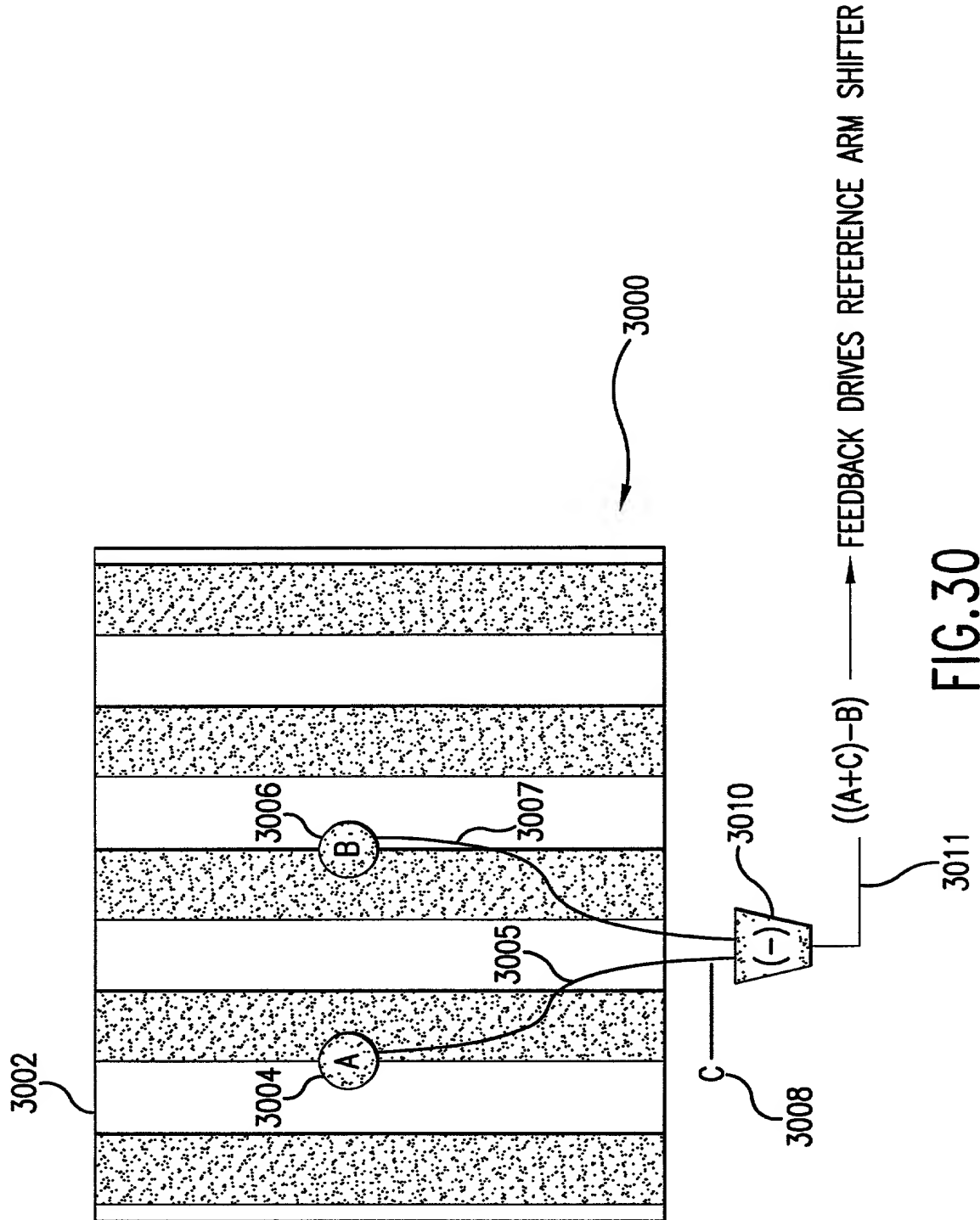


FIG.30

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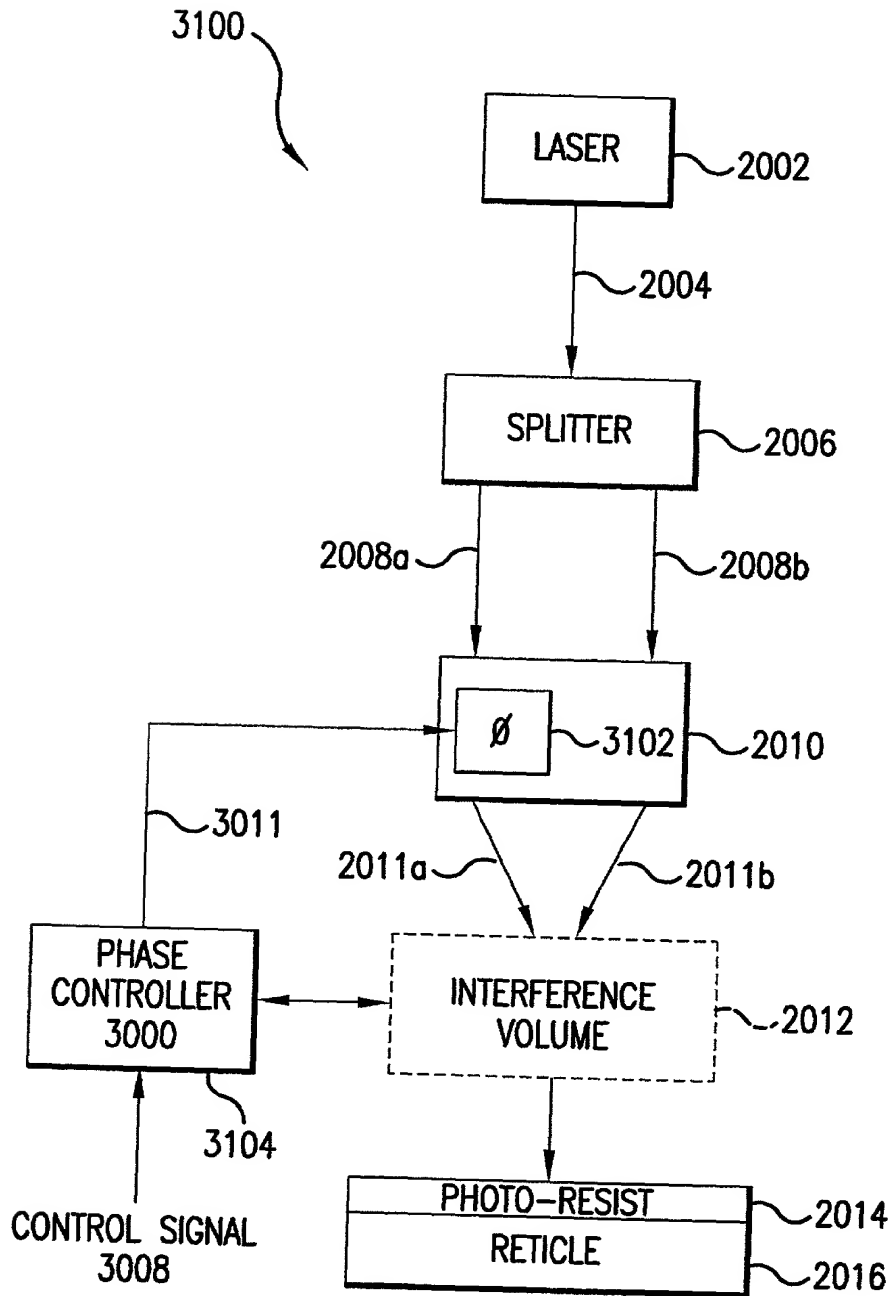


FIG.31

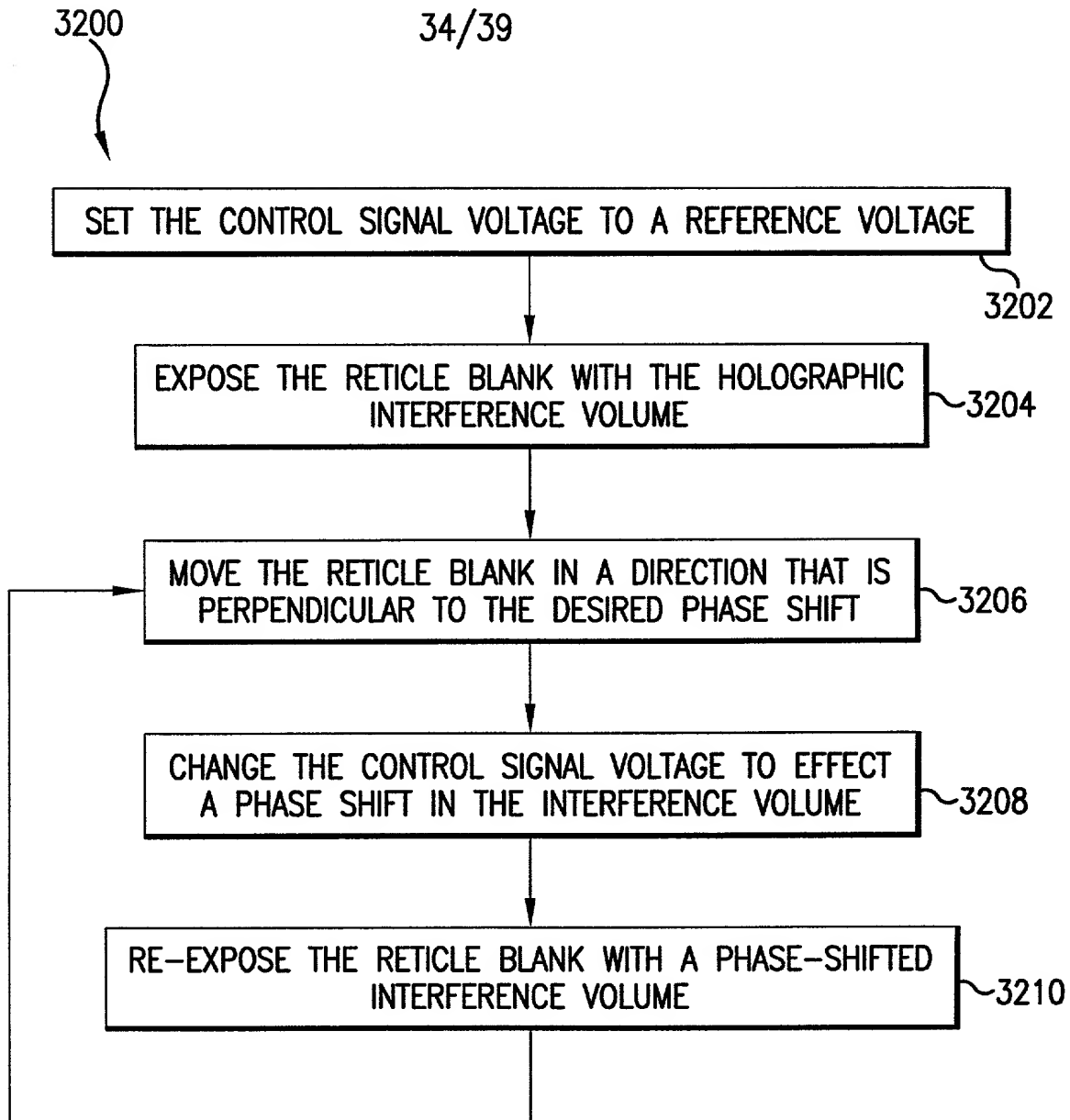


FIG.32

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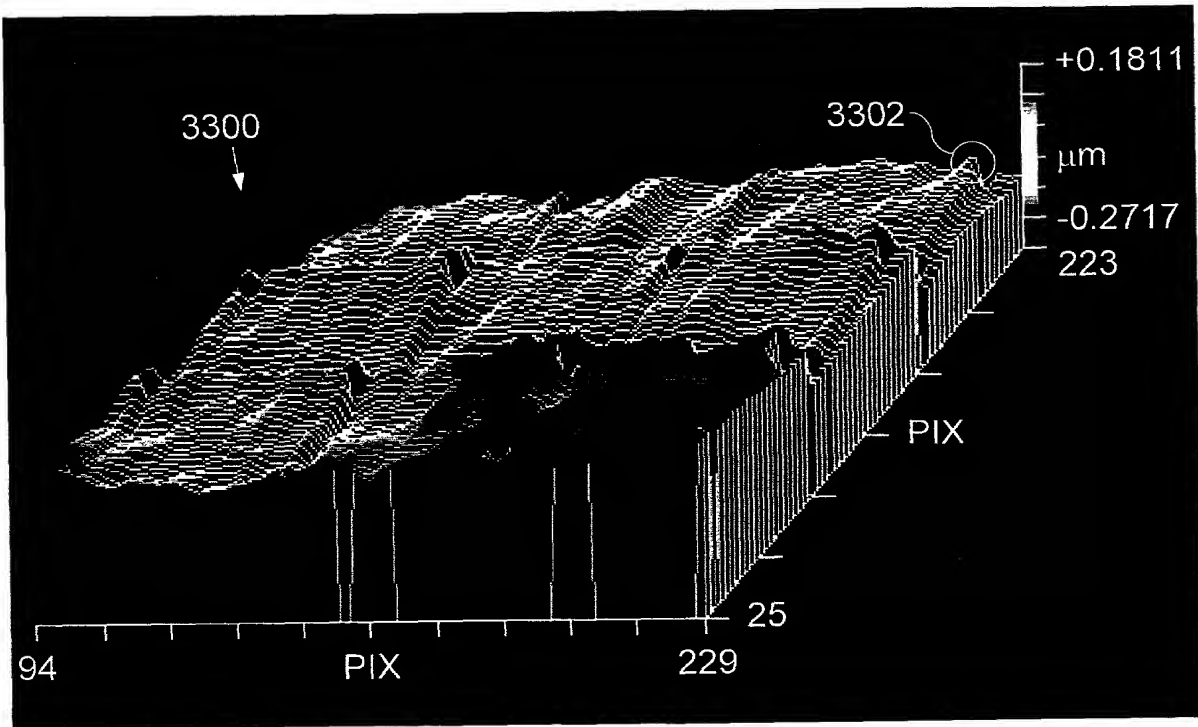


FIG.33

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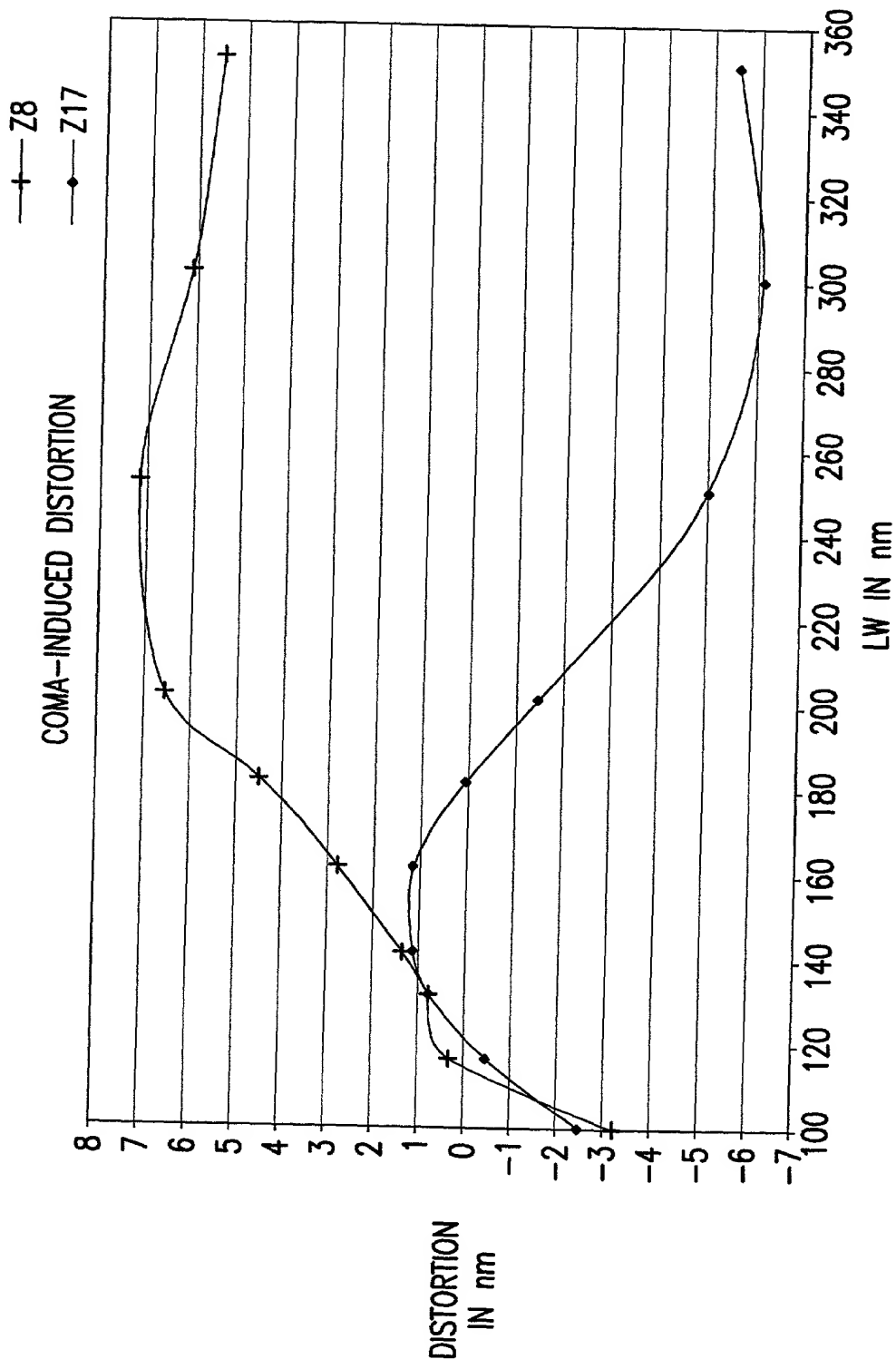


FIG.34

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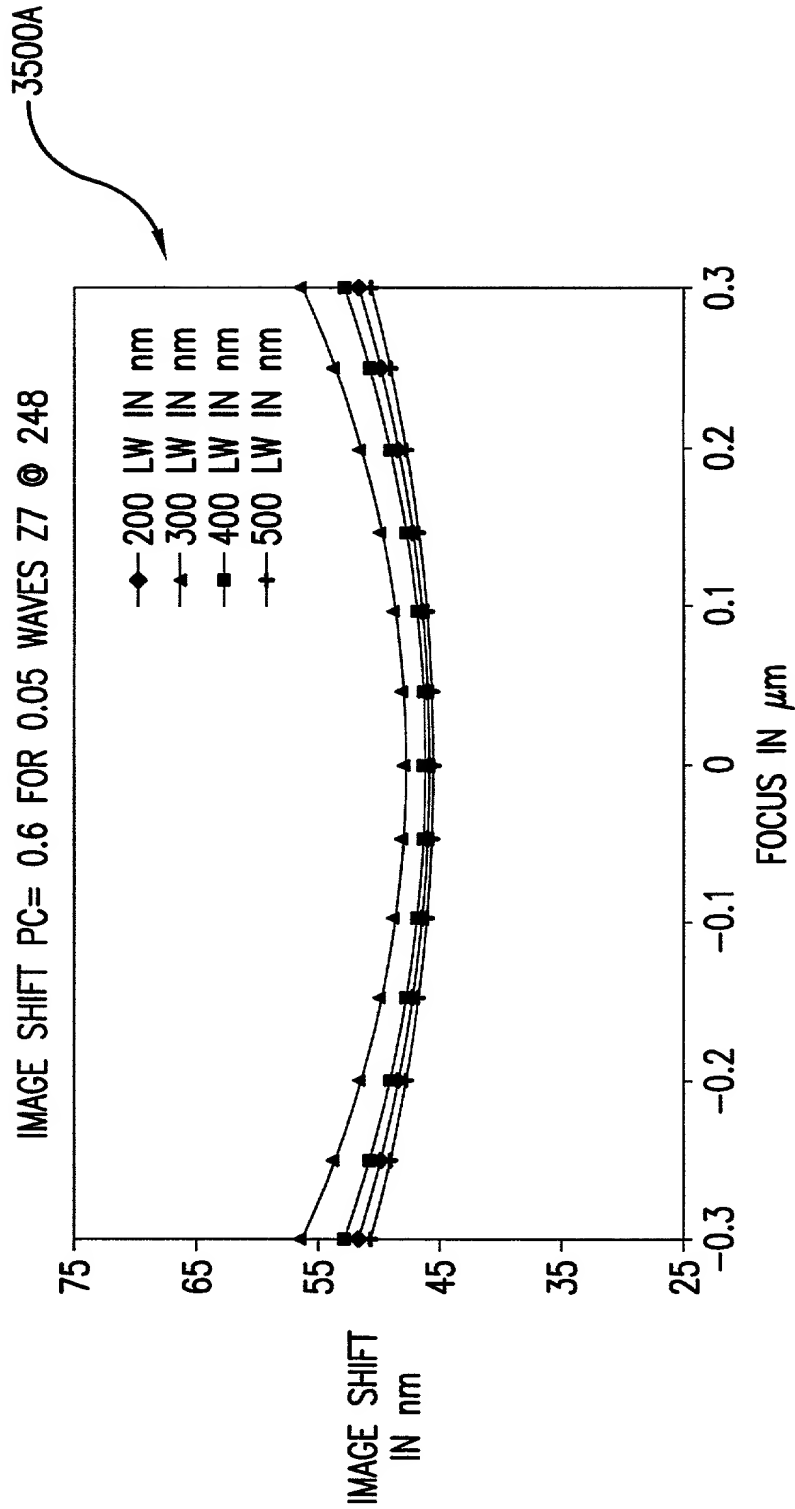


FIG.35A

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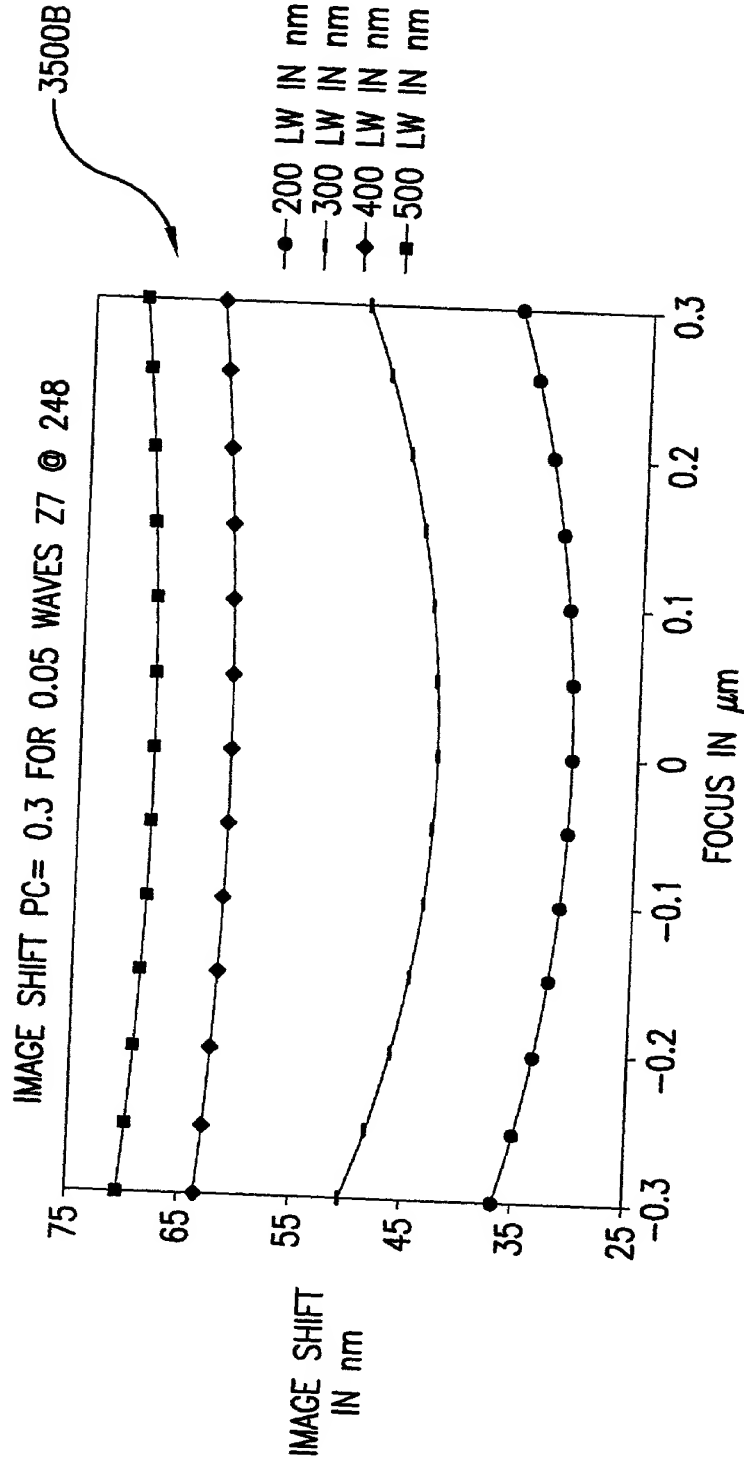


FIG.35B

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3600


LINEWIDTH	DIFFRACTION ORDER			
	1ST	2ND	3RD	4TH
100 nm	a			
200 nm	b	a		
300 nm	c		a	
400 nm	d	b		a
600 nm	e	c		
800 nm		d	b	
900 nm			c	
1000 nm				b
1200 nm		e	d	c

FIG.36

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